

EN 55022:2010
EN 55024:2010
EN 61000-3-2:2006 + A1:2009 + A2:2009
EN 61000-3-3:2008
TEST REPORT

For

Yealink (Xiamen) Network Technology Co., Ltd.

4th-5th Floor, South Building, NO. 63 WangHai Road, 2nd Software Park, Xiamen, China

Model: T42G

Report Type: Original Report	Product Type: IP Phone
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Report Number: RSZ130221003-01	
Report Date: 2013-03-27	
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Note: This test report is prepared for the customer shown above and for the equipment described herein. It may not be duplicated or used in part without prior written consent from Bay Area Compliance Laboratories Corp.

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GENERAL INFORMATION

The Yealink (Xiamen) Network Technology Co., Ltd. 's product, model number: T42G (the "EUT") in this report is an IP Phone, which was measured approximately: 21.0 cm (L) x 10.0 cm (W) x 18.0 cm (H), rated input voltage: DC 5V from adapter or PoE 48V power. The highest operating frequency is 200 MHz.

Adapter Information: AC/DC SWITCHING ADAPTER
Model: OH-1048A0501200U2-VDE
Input: 100-240V~50/60Hz, 250mA
Output: DC 5V, 1.2A

**All measurement and test data in this report was gathered from production sample serial number: 1302039 (Assigned by BACL, Shenzhen). The EUT supplied by the applicant was received on 2013-02-21.*

Objective

This test report is prepared on behalf of Yealink (Xiamen) Network Technology Co., Ltd. in accordance with EN 55022: Information technology equipment-Radio disturbance characteristics-Limits and methods of measurement. EN 55024: Information technology equipment- Immunity characteristics – Limits and methods of measurement. EN 61000-3-2, Limits – Limits for harmonic current emissions (equipment input current up to and including 16 A per phase), and also in accordance with EN 61000-3-3, Limits Section 3; Limitation of voltage fluctuations and flicker in low-voltage supply systems for equipment with rated current <16A.

The objective of the manufacturer is to determine compliance with EN 55022, EN 55024, EN 61000-3-2 and EN 61000-3-3.

Related Submittal(s)/Grant(s)

No related submittal(s).

Test Methodology

All measurements contained in this report were conducted with CISPR 16-1-1:2010, specification for radio disturbance and immunity measuring apparatus and methods P1-1: radio disturbance and immunity measuring apparatus. CISPR 16-1-4:2010, Specification for radio disturbance and immunity measuring apparatus and methods-Part 1-4: Radio disturbance and immunity measuring apparatus -Ancillary equipment -Radiated disturbances. CISPR 16-2-1:2010, specification for radio disturbance and immunity measuring apparatus and methods P2-1: methods of measurement of disturbance and immunity conducted disturbance measurements. CISPR 16-2-3:2010, specification for radio disturbance and immunity measuring apparatus and methods P2-3 methods of measurement of disturbances and immunity radiated disturbance measurements. CISPR 16-4-2:2011, Specification for radio disturbance and immunity measuring apparatus and methods-Part 4-2: Uncertainties, statistics and limit modeling-Uncertainty in EMC measurements.

All radiated and conducted emissions measurement was performed at Bay Area Compliance Laboratories Corp. (Shenzhen). The radiated testing was performed at an antenna-to-EUT distance of 3 Meters.

Test Facility

The Test site used by Bay Area Compliance Laboratories Corp. (Shenzhen) to collect test data is located on the 6/F, the 3rd Phase of WanLi Industrial Building, ShiHua Road, FuTian Free Trade Zone Shenzhen, Guangdong, China.

Test site at Bay Area Compliance Laboratories Corp. (Shenzhen) has been fully described in reports submitted to the Federal Communication Commission (FCC). The details of these reports have been found to be in compliance with the requirements of Section 2.948 of the FCC Rules on December 06, 2010. The facility also complies with the radiated and AC line conducted test site criteria set forth in ANSI C63.4-2003.

The Federal Communications Commission has the reports on file and is listed under FCC Registration No.: 382179. The test site has been approved by the FCC for public use and is listed in the FCC Public Access Link (PAL) database.

SYSTEM TEST CONFIGURATION

Justification

The system was configured for testing in a manufacturer testing fashion.

EUT Exercise Software

No exercise software was used.

Equipment Modifications

No modification was made to the EUT.

Support Equipment List and Details

Manufacturer	Description	Model	Serial Number
DELL	PC	VOSTRO 220S	127BP2X
DELL	Keyboard	L100	CNORH656658907BL04TY
DELL	Mouse	MOC5UO	G1B0096D
DELL	Monitor	E178WFPC	CN-OWY564-64180-7C4-2SQH
SAST	Modem	AEM-2100	0293
Yealink	VOIP Phone	SIP-T42G	N/A
Netgear	PoE	FS108P	N/A

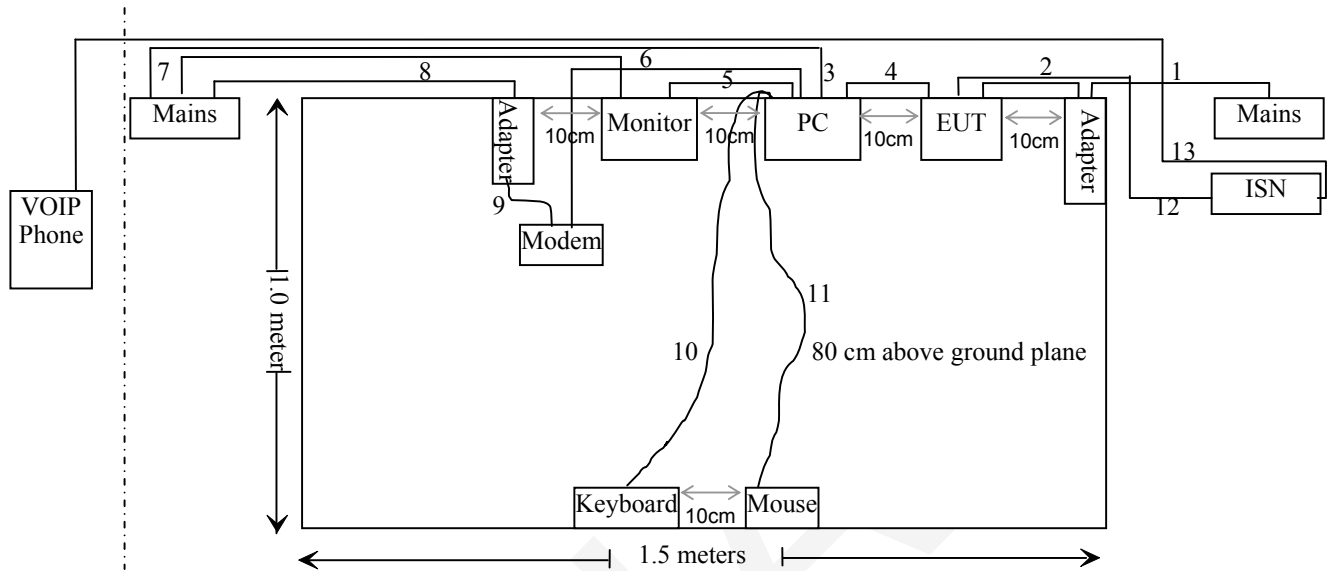
External I/O Cable

Cable Description	Length (m)	From/Port	To
Unshielding Detachable AC Cable	1.2	Adapter of EUT	Mains
Unshielding Undetachable DC Cable	0.8	Adapter of EUT	EUT
Unshielding Detachable RJ45 Cable	1.2	PC	EUT
Shielding Detachable VGA Cable	1.5	PC	Monitor
Shielding Detachable RS232 Cable	1.2	PC	Modem
Unshielding Detachable AC Cable	1.2	Monitor	Mains
Unshielding Detachable AC Cable	1.0	Adapter of modem	Mains
Unshielding Undetachable DC Cable	0.8	Adapter of modem	Modem
Shielding Undetachable K/B Cable	1.5	PC	Keyboard
Shielding Undetachable Mouse Cable	1.5	PC	Mouse
Unshielding Detachable AC Cable	1.2	PC	Mains
Unshielding Detachable RJ45 Cable	1.2	ISN	EUT
Unshielding Detachable RJ45 Cable	4.0	ISN	Voip phone
Unshielded Detachable AC Cable	1.0	Adapter of PoE	Mains
Unshielded Undetachable DC Cable	0.8	Adapter of PoE	POE switch
Unshielded Detachable RJ45 Cable	1.0	EUT	POE switch
Unshielded Detachable RJ45 Cable	3.0	VOIP phone	POE switch

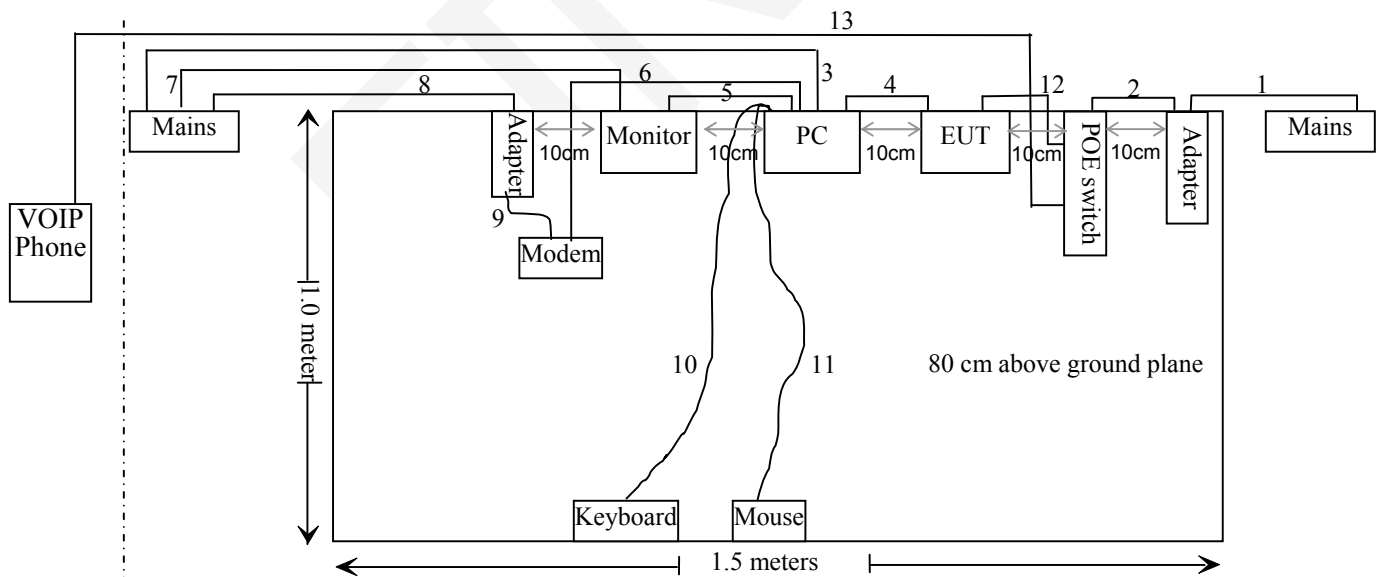
Block Diagram of Test Setup

For conducted emission

Powered by Adapter:



Powered by PoE:



SUMMARY OF TEST REPORT**EN 55022**

RULE	DESCRIPTION	RESULTS
§ 5.1	Conducted Disturbance at Mains Terminals	Compliance
§ 5.2	Conducted Disturbance at Telecommunication Port	Compliance
§ 6	Radiated Disturbance	Compliance

EN 55024

RULE	DESCRIPTION	RESULTS
§4.2.1	Electrostatic Discharge IEC 61000-4-2	Compliance
§4.2.2	Electrical Fast Transients IEC 61000-4-4	Compliance
§4.2.3.1	Continuous Radiated Disturbance IEC 61000-4-3	Compliance
§4.2.3.2	Continuous Conducted Disturbance IEC 61000-4-6	Compliance
§4.2.4	Power Frequency Magnetic Fields IEC 61000-4-8	Compliance
§4.2.5	Surges IEC 61000-4-5	Compliance
§4.2.6	Voltage Dips And Interruptions, IEC 61000-4-11	Compliance

EN 61000-3-2

Rule	Description	Results
EN 61000-3-2	Harmonic Current Emissions	Compliance

EN 61000-3-3

Rule	Description	Results
EN 61000-3-3	Voltage Fluctuation and Flicker	Compliance

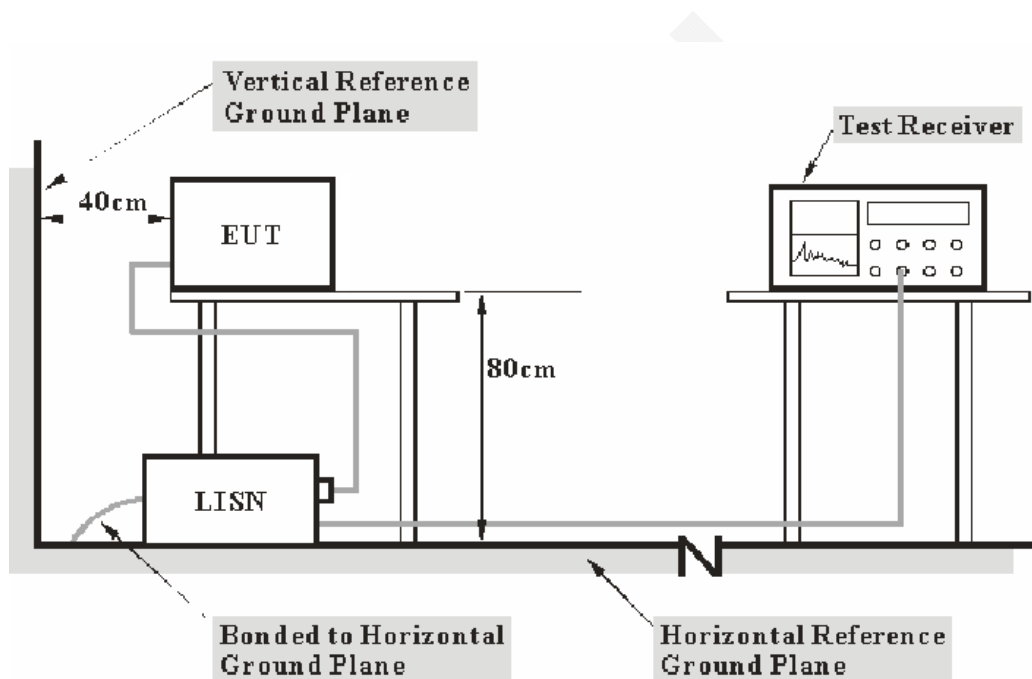
EN 55022 §5.1-CONDUCTED DISTURBANCE AT MAINS TERMINALS §5.2-CONDUCTED DISTURBANCE AT TELECOMMUNICATION PORT

Measurement Uncertainty

All measurements involve certain levels of uncertainties, especially in field of EMC. The factors contributing to uncertainties are spectrum analyzer, cable loss, and LISN.

Based on CISPR 16-4-2, The Treatment of Uncertainty in EMC Measurements, the best estimate of the uncertainty of any conducted emissions measurement at Bay Area Compliance Laboratories Corp. (Shenzhen) is 2.4 dB, ($k=2$, 95% level of confidence), and the uncertainty will not be taken into consideration for all the test data recorded in the report.

Test System Setup



- Note: 1. Support units were connected to second LISN.
2. Both of LISNs (AMN) 80 cm from EUT and at the least 80 cm from other units and other metal planes support units.

The measurement procedure is in according with CISPR 16-1-1:2010, CISPR 16-2-1:2010. The related limit was specified in the EN 55022 Class B.

The external I/O cables were draped along the test table and formed a bundle 30 to 40 cm long in the middle.

The spacing between the peripherals was 10 cm.

The adapter was connected to a 230VAC/50 Hz power source.

EMI Test Receiver Setup

The EMI test receiver was set to investigate the spectrum from 150 kHz to 30 MHz.

During the conducted emission test, the EMI test receiver was set with the following configurations:

Frequency Range	IF B/W
150 kHz – 30 MHz	9 kHz

Test Equipment List and Details

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
Rohde & Schwarz	EMI Test Receiver	ESCS30	100176	2012-11-24	2013-11-23
Rohde & Schwarz	L.I.S.N.	ESH2-Z5	892107/021	2012-08-22	2013-08-21
Rohde & Schwarz	Attenuator	ESH3Z2	DE25985	2012-07-08	2013-07-07
SCHWARZBECK	8 Wire ISN	NTFM 8158	8158-0011	2012-11-17	2013-11-16
BACL	CE Test software	BACL-CE	V1.0	-	-

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements, traceable to National Primary Standards and International System of Units (SI).

Test Procedure

Maximizing procedure was performed on the six (6) highest emissions to ensure EUT compliance using all installation combination.

All data was recorded in the Quasi-peak and average detection mode.

Corrected Factor & Margin Calculation

The Corrected factor is calculated by adding LISN/ISN VDF (Voltage Division Factor), Cable Loss and Pulse Limiter Attenuation. The basic equation is as follows:

Correction Factor = LISN VDF + Cable Loss + Pulse Limiter Attenuation

The “**Margin**” column of the following data tables indicates the degree of compliance with the applicable limit. For example, a margin of 7dB means the emission is 7 dB below the limit. The equation for margin calculation is as follows:

$$\text{Margin} = \text{Limit} - \text{Corrected Amplitude}$$

Test Results Summary

According to the recorded data in following table, with the worst margin reading of:

2.59 dB at 4.940 MHz in the **Line** conducted mode (Powered by PoE)

Refer to CISPR16-4-2: 2011 and CISPR 16-4-1: 2009, the measured level is in compliance with the limit if

$$L_m + U_{(L_m)} \leq L_{\text{lim}} + U_{\text{cispr}} \\ \text{or } U_{(L_m)} \leq \text{Margin} + U_{\text{cispr}}$$

The measurement result of EUT is below the limit level by a margin 2.59 dB and

$$U_{(L_m)}(2.4\text{dB}) \leq \text{Margin}(2.59\text{ dB}) + U_{\text{cispr}}(3.4\text{dB}),$$

so the EUT complies with the limit of the EN 55022 Class B.

Test Data

Environmental Conditions

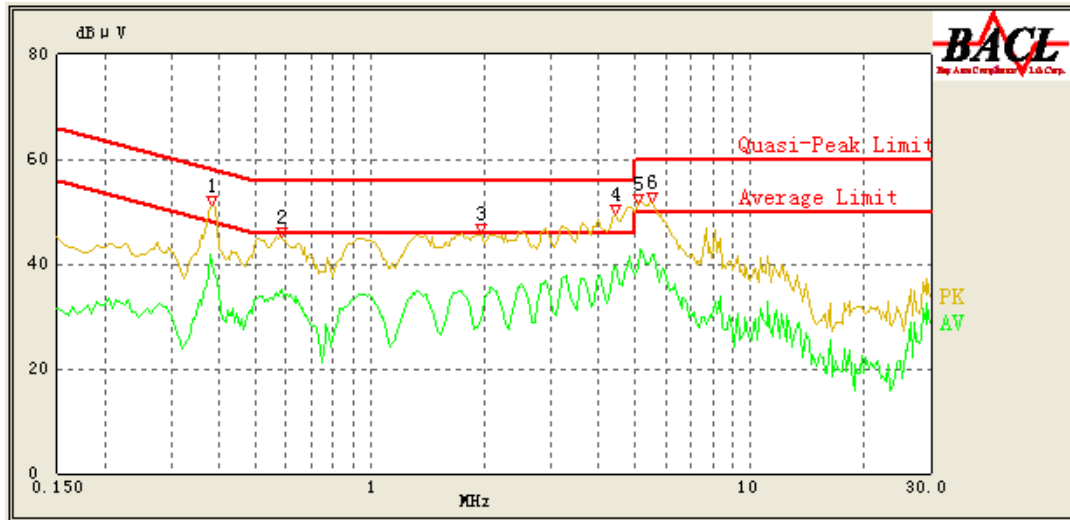
Temperature:	25°C
Relative Humidity:	56 %
ATM Pressure:	100.0 kPa

The testing was performed by Andrew Shu on 2013-02-26.

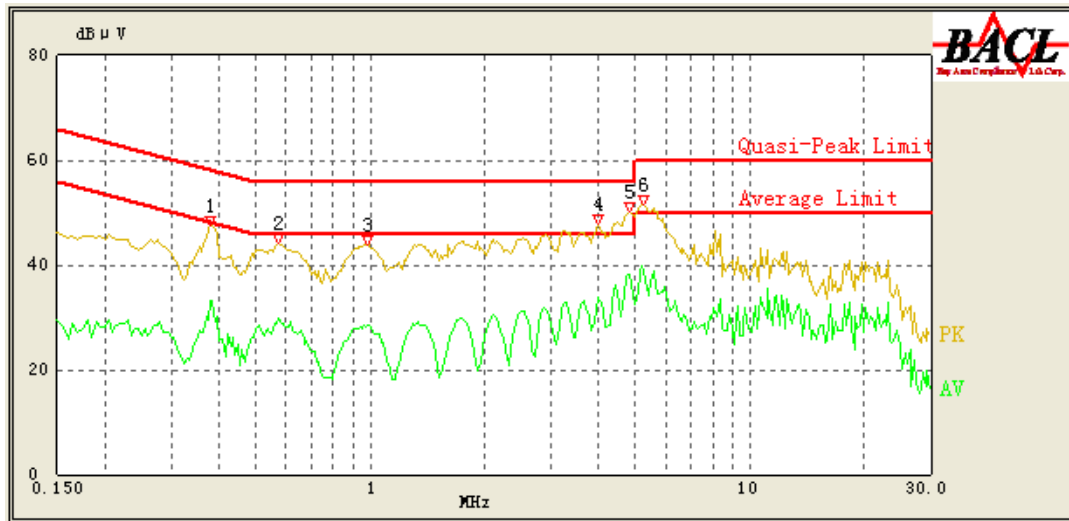
Test Mode: Running

Powered by Adapter:

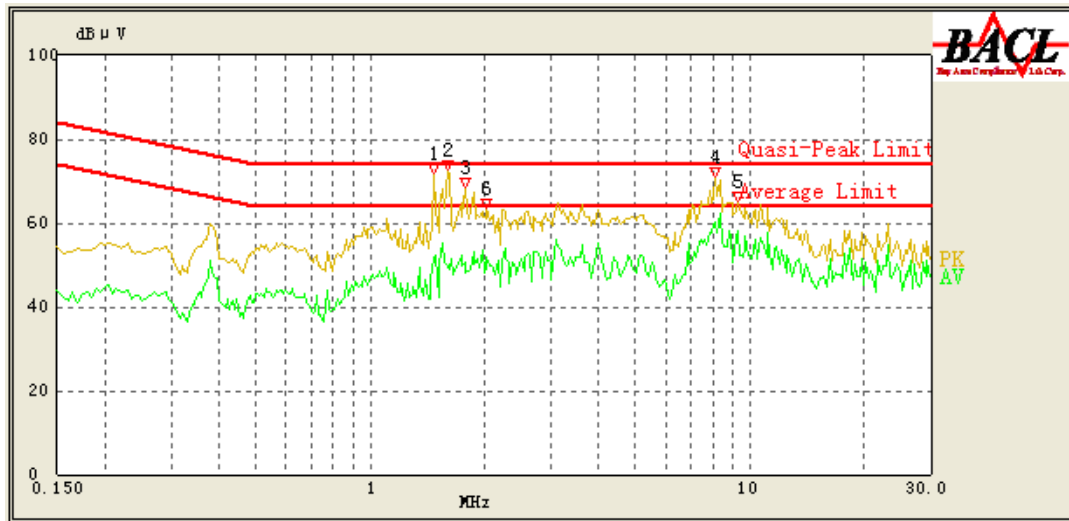
AC 230V/50 Hz, Line



Frequency (MHz)	Corrected Amplitude (dBμV)	Correction Factor (dB)	Limit (dBμV)	Margin (dB)	Detector (PK/Ave./QP)
4.430	39.43	10.20	46.00	6.57	Ave.
5.535	41.97	10.23	50.00	8.03	Ave.
0.385	40.27	10.10	49.29	9.02	Ave.
5.070	39.52	10.20	50.00	10.48	Ave.
4.410	45.08	10.20	56.00	10.92	QP
0.585	35.01	10.20	46.00	10.99	Ave.
0.385	47.88	10.10	59.29	11.41	QP
5.080	48.43	10.20	60.00	11.57	QP
5.535	48.35	10.23	60.00	11.65	QP
0.585	42.89	10.20	56.00	13.11	QP
1.985	30.89	10.20	46.00	15.11	Ave.
1.965	37.23	10.20	56.00	18.77	QP

AC 230V/50 Hz, Neutral:

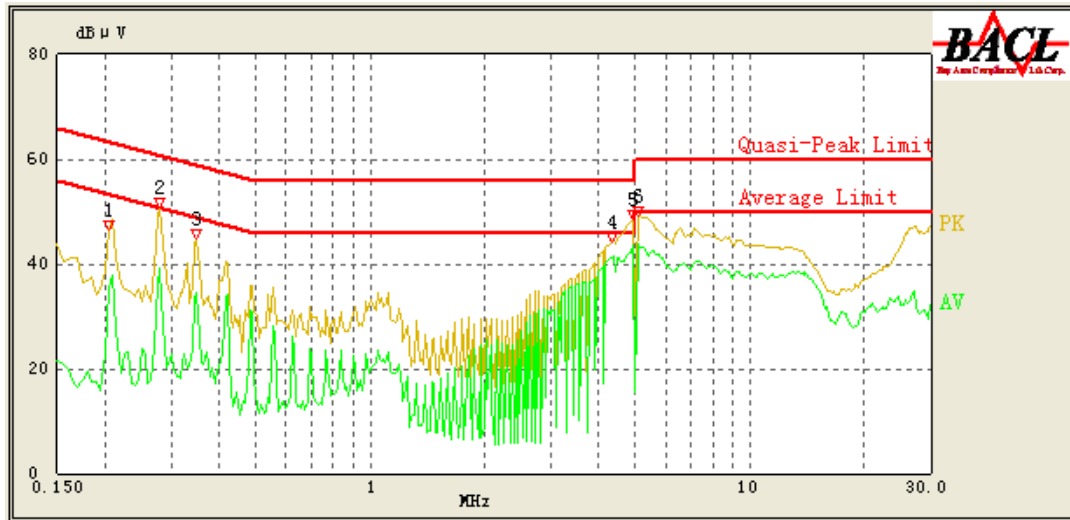
Frequency (MHz)	Corrected Amplitude (dBμV)	Correction Factor (dB)	Limit (dBμV)	Margin (dB)	Detector (PK/Ave./QP)
4.785	38.18	10.20	46.00	7.82	Ave.
4.820	45.98	10.20	56.00	10.02	QP
5.235	39.29	10.21	50.00	10.71	Ave.
5.225	47.82	10.21	60.00	12.18	QP
4.005	33.67	10.20	46.00	12.33	Ave.
0.380	45.32	10.10	59.43	14.11	QP
4.000	41.85	10.20	56.00	14.15	QP
0.575	40.89	10.20	56.00	15.11	QP
0.980	40.18	10.20	56.00	15.82	QP
0.575	29.86	10.20	46.00	16.14	Ave.
0.380	33.05	10.10	49.43	16.38	Ave.
0.975	28.14	10.20	46.00	17.86	Ave.

RJ45 Port:

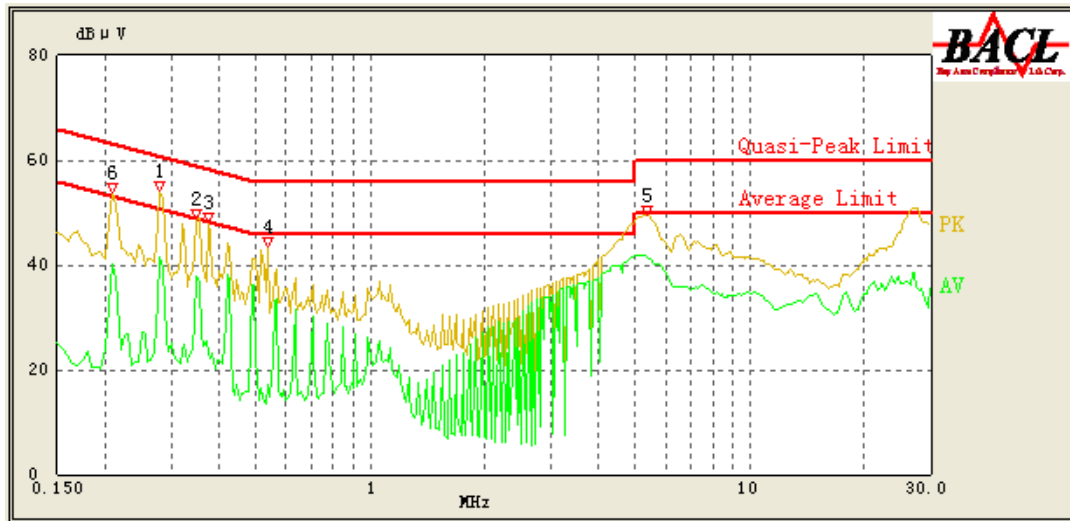
Frequency (MHz)	Corrected Amplitude (dBμV)	Correction Factor (dB)	Limit (dBμV)	Margin (dB)	Detector (PK/Ave./QP)
8.100	60.34	19.66	64.00	3.66	Ave.
9.255	58.22	19.69	64.00	5.78	Ave.
8.100	67.92	19.66	74.00	6.08	QP
2.025	51.75	19.70	64.00	12.25	Ave.
1.465	51.53	19.81	64.00	12.47	Ave.
1.785	50.71	19.74	64.00	13.29	Ave.
1.590	50.24	19.78	64.00	13.76	Ave.
9.260	60.21	19.69	74.00	13.79	QP
2.025	55.48	19.70	74.00	18.52	QP
1.785	54.78	19.74	74.00	19.22	QP
1.465	53.08	19.81	74.00	20.92	QP
1.600	48.07	19.78	74.00	25.93	QP

Powered by PoE:

AC 230V/50 Hz, Line



Frequency (MHz)	Corrected Amplitude (dBμV)	Correction Factor (dB)	Limit (dBμV)	Margin (dB)	Detector (PK/Ave./QP)
4.940	43.41	10.20	46.00	2.59	Ave.
4.315	41.23	10.20	46.00	4.77	Ave.
5.080	43.88	10.20	50.00	6.12	Ave.
0.280	39.19	10.16	52.29	13.10	Ave.
0.280	47.28	10.16	62.29	15.01	QP
0.350	34.45	10.20	50.29	15.84	Ave.
0.205	35.58	10.10	54.43	18.85	Ave.
0.350	40.86	10.20	60.29	19.43	QP
0.205	43.77	10.10	64.43	20.66	QP
4.940	27.50	10.20	56.00	28.50	QP
5.080	26.06	10.20	60.00	33.94	QP
4.315	22.03	10.20	56.00	33.97	QP

AC 230V/50 Hz, Neutral:

Frequency (MHz)	Corrected Amplitude (dBμV)	Correction Factor (dB)	Limit (dBμV)	Margin (dB)	Detector (PK/Ave./QP)
5.335	41.56	10.22	50.00	8.44	Ave.
0.280	41.65	10.10	52.29	10.64	Ave.
0.280	50.95	10.10	62.29	11.34	QP
0.350	37.82	10.10	50.29	12.47	Ave.
0.210	40.26	10.10	54.29	14.03	Ave.
0.210	49.75	10.10	64.29	14.54	QP
0.350	45.26	10.10	60.29	15.03	QP
0.375	23.53	10.10	49.57	26.04	Ave.
0.540	17.25	10.20	46.00	28.75	Ave.
0.375	30.44	10.10	59.57	29.13	QP
0.540	22.92	10.20	56.00	33.08	QP
5.335	20.40	10.22	60.00	39.60	QP

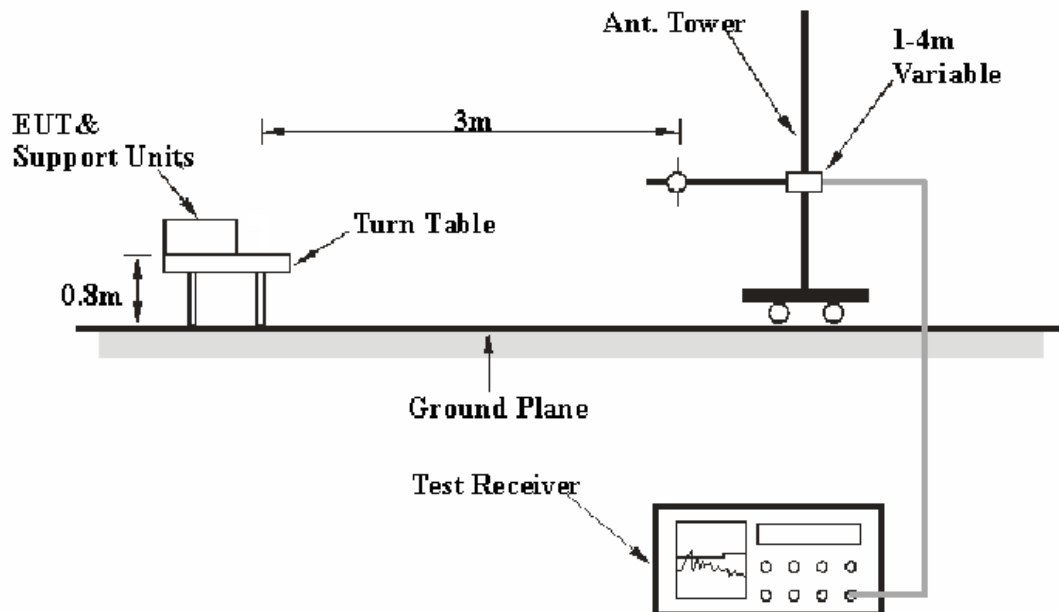
EN 55022 §6-RADIATED DISTURBANCE

Measurement Uncertainty

All measurements involve certain levels of uncertainties, especially in field of EMC. The factors contributing to uncertainties are spectrum analyzer, cable loss, antenna factor calibration, antenna directivity, antenna factor variation with height, antenna phase center variation, antenna factor frequency interpolation, measurement distance variation, site imperfections, mismatch (average), and system repeatability.

Based on CISPR 16-4-2, The Treatment of Uncertainty in EMC Measurements, the best estimate of the uncertainty of radiation emissions measurement at Bay Area Compliance Laboratories Corp. (Shenzhen) is 4.0 dB, ($k=2$, 95% level of confidence), and the uncertainty will not be taken into consideration for all the test data recorded in the report.

Test System Setup



The radiated emission tests were performed in the 3 meters chamber A test site, using the setup accordance with the CISPR16-1-4:2010, CISPR 16-2-3:2010. The limit was specified in EN 55022 Class B.

The external I/O cables were draped along the test table and formed a bundle 30 to 40 cm long in the middle.

The spacing between the peripherals was 10 cm.

The adapter was connected to a 230 VAC/50 Hz power source.

EMI Test Receiver Setup

The system was investigated from 30 MHz to 2 GHz.

During the radiated emission test, the EMI test receiver Setup was set with the following configurations:

Frequency Range	RBW	Video B/W	IF B/W	Detector
30 MHz – 1000 MHz	120 kHz	300 kHz	120 kHz	QP
Above 1 GHz	1MHz	3 MHz	/	PK
	1MHz	10 Hz	/	Ave.

Test Procedure

Maximizing procedure was performed on the highest emissions to ensure that the EUT complied with all installation combinations.

All data was recorded in the Quasi-peak detection mode for below 1 GHz, and Peak and Average for above 1 GHz.

Corrected Amplitude & Margin Calculation

The Corrected Amplitude is calculated by adding the Antenna Factor and Cable Loss, and subtracting the Amplifier Gain from the Meter Reading. The basic equation is as follows:

$$\text{Corrected Amplitude} = \text{Meter Reading} + \text{Antenna Factor} + \text{Cable Loss} - \text{Amplifier Gain}$$

The “**Margin**” column of the following data tables indicates the degree of compliance with the applicable limit. For example, a margin of 7 dB means the emission is 7 dB below the limit for Class B. The equation for margin calculation is as follows:

$$\text{Margin} = \text{Limit} - \text{Corrected Amplitude.}$$

Test Equipment List and Details

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
HP	Amplifier	8447E	1937A01046	2012-11-24	2013-11-23
Rohde & Schwarz	EMI Test Receiver	ESCI	101122	2012-08-08	2013-08-07
Sunol Sciences	Broadband Antenna	JB1	A040904-2	2011-11-28	2014-11-27
Rohde & Schwarz	Signal Analyzer	FSIQ26	8386001028	2012-11-24	2013-11-23
Super Ultra	Pre-Amplifier	ZVA-213+	N/A	2012-11-24	2013-11-23
Sunol Sciences	Horn Antenna	DRH-118	A052304	2011-12-01	2014-11-30
R&S	Auto test Software	EMC32	V6.30	-	-

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements, traceable to National Primary Standards and International System of Units (SI).

Test Results Summary

According to the data in the following table, with the worst margin reading of:

2.3 dB at 999.990175 MHz in the Vertical polarization (Powered by Adapter)

Refer to CISPR16-4-2: 2011 and CISPR 16-4-1: 2009, the measured level is in compliance with the limit if

$$L_m + U_{(L_m)} \leq L_{\text{lim}} + U_{\text{cispr}} \\ \text{or } U_{(L_m)} \leq \text{Margin} + U_{\text{cispr}}$$

The measurement result of EUT is below the limit level by a margin 2.3 dB and $U_{(L_m)}(4\text{dB}) \leq \text{Margin}(2.3 \text{ dB}) + U_{\text{cispr}}(6.3\text{dB})$, so the EUT complies with the limit of the EN 55022 Class B

Test Data

Environmental Conditions

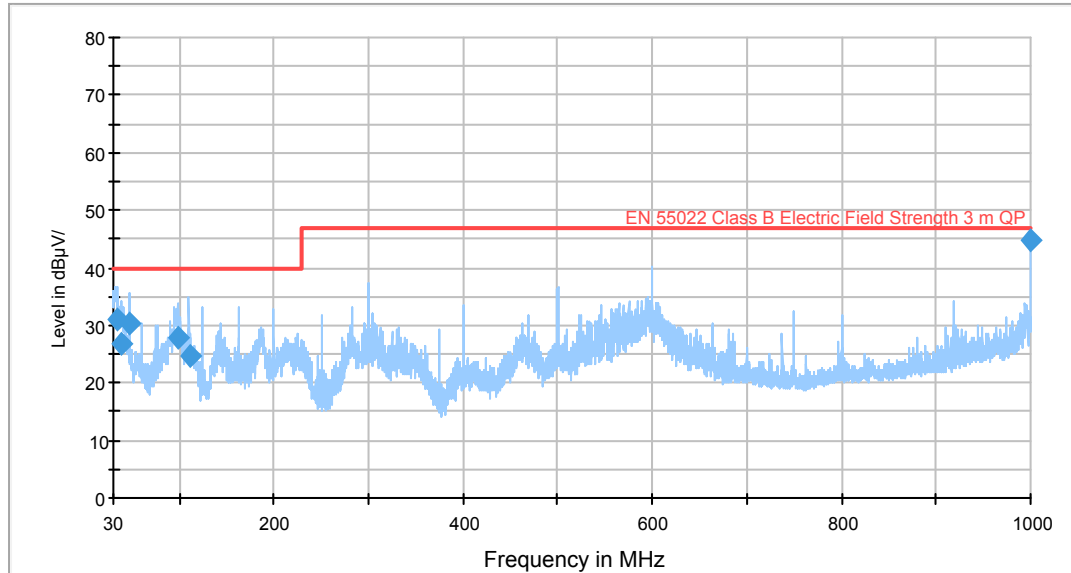
Temperature:	24°C
Relative Humidity:	56 %
ATM Pressure:	100.1 kPa

The testing was performed by Andrew Shu on 2013-02-28.

Test Mode: Running

Powered by Adapter:**1) 30~1000 MHz**

EN55022



Frequency (MHz)	Corrected Amplitude (dBμV/m)	Antenna height (cm)	Antenna Polarity	Turntable position (degree)	Correction Factor (dB/m)	Limit (dBμV/m)	Margin (dB)
999.990175	44.7	105.0	V	142.0	-2.7	47.0	2.3*
33.623000	31.1	106.0	V	0.0	-9.6	40.0	8.9
47.836975	30.3	104.0	V	1.0	-19.2	40.0	9.7
97.515625	27.9	196.0	H	242.0	-18.0	40.0	12.1
37.842575	26.9	140.0	V	0.0	-12.8	40.0	13.1
110.362225	24.7	135.0	V	258.0	-14.8	40.0	15.3

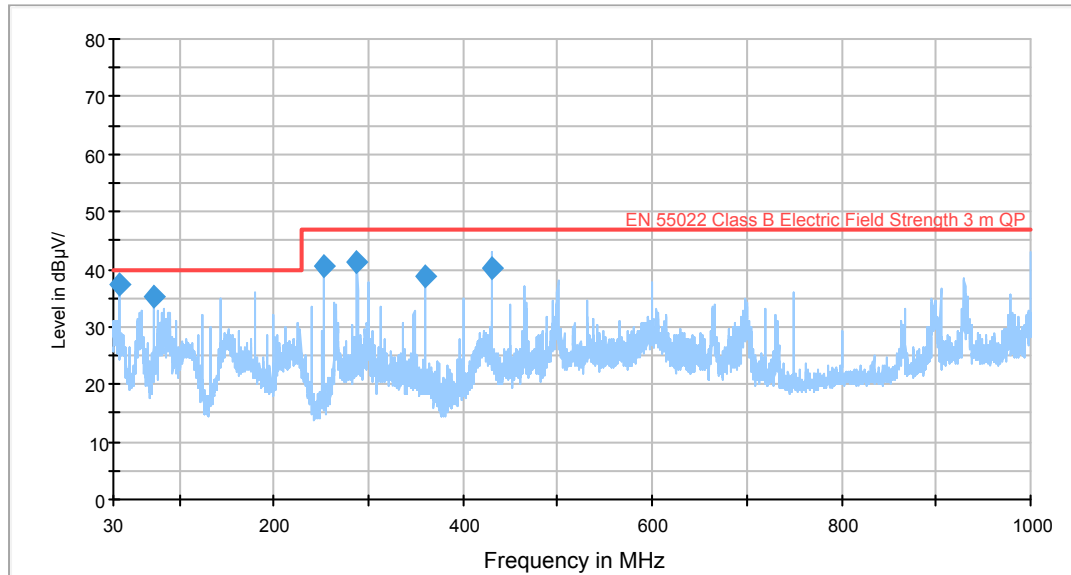
*Within measurement uncertainty.

2) Above 1 GHz

Frequency (MHz)	Receiver		Turntable Degree	Rx Antenna		Corrected Factor (dB/m)	Corrected Amplitude (dBμV/m)	EN 55022	
	Reading (dBμV)	Detector (PK/QP/Ave.)		Height (m)	Polar (H/V)			Limit (dBμV/m)	Margin (dB)
1000.0	46.30	Ave.	32	1.5	H	-1.20	45.10	50.00	4.90
1000.0	45.68	Ave.	73	1.3	V	-1.20	44.48	50.00	5.52
1853.7	39.49	Ave.	113	1.1	H	2.63	42.12	50.00	7.88
1400.8	39.11	Ave.	82	1.2	V	0.68	39.79	50.00	10.21
1885.8	48.12	PK	113	1.1	H	2.63	50.75	70.00	19.25
1000.0	51.86	PK	32	1.5	H	-1.20	50.66	70.00	19.34
1000.0	50.95	PK	73	1.3	V	-1.20	49.75	70.00	20.25
1400.8	47.77	PK	82	1.2	V	0.68	48.45	70.00	21.55

Powered by PoE:**1) 30~1000 MHz**

EN55022



Frequency (MHz)	Corrected Amplitude (dBμV/m)	Antenna height (cm)	Antenna Polarity	Turntable position (degree)	Correction Factor (dB/m)	Limit (dBμV/m)	Margin (dB)
36.003500	37.5	100.0	V	235.0	-11.5	40.0	2.5*
71.952500	35.1	126.0	V	12.0	-20.6	40.0	4.9
288.020000	41.3	213.0	H	156.0	-14.2	47.0	5.7
252.008750	40.4	107.0	V	35.0	-15.8	47.0	6.6
430.003750	40.3	112.0	V	158.0	-11.4	47.0	6.7
360.042500	38.6	174.0	H	79.0	-13.3	47.0	8.4

*Within measurement uncertainty.

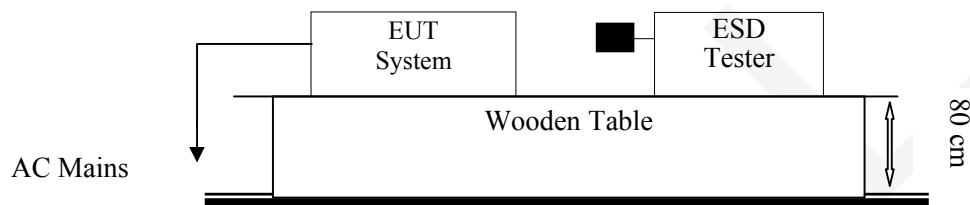
2) Above 1 GHz

Frequency (MHz)	Receiver		Turntable Degree	Rx Antenna		Corrected Factor (dB/m)	Corrected Amplitude (dBμV/m)	EN 55022	
	Reading (dBμV)	Detector (PK/QP/Ave.)		Height (m)	Polar (H/V)			Limit (dBμV/m)	Margin (dB)
2392.8	41.53	Ave.	3	1.6	H	5.48	47.01	50	2.99*
2112.2	39.31	Ave.	198	2.0	V	3.94	43.25	50	6.75
1861.7	39.76	Ave.	24	1.7	H	2.63	42.39	50	7.61
1861.7	59.25	PK	24	1.7	H	2.63	61.88	70	8.12
2032.1	38.32	Ave.	242	1.0	H	3.23	41.55	50	8.45
2032.1	57.91	PK	242	1.0	V	3.23	61.14	70	8.86
1771.5	58.00	PK	20	1.4	H	2.32	60.32	70	9.68
1771.5	38.00	Ave.	20	1.4	V	2.32	40.32	50	9.68
1400.8	39.02	Ave.	35	1.1	V	0.74	39.76	50	10.24
2112.2	55.65	PK	198	2.0	H	3.94	59.59	70	10.41
2392.8	53.01	PK	3	1.6	V	5.48	58.49	70	11.51
1400.8	53.08	PK	35	1.1	V	0.74	53.82	70	16.18

EN 55024 §4.2.1-ELECTROSTATIC DISCHARGES (IEC 61000-4-2)**Test Equipment**

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	ESD Tester	Dito	302105	2012-09-13	2013-09-12

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements, traceable to National Primary Standards and International System of Units (SI).

Test System Setup

Remark: ■ is the tip of the electrode

IEC 61000-4-2 specifies that a tabletop EUT shall be placed on a non-conducting table which is 80 centimeters above a ground reference plane and that floor mounted equipment shall be placed on a insulating support approximately 10 centimeters above a ground plane. During the tests, the EUT is positioned over a ground reference plane in conformance with this requirement.

For tabletop equipment, a 1.5 by 1.0-meter metal sheet (HCP) is placed on the table and connected to the ground plane via a metal strap with two 470 k Ohms resistors in series. The EUT and attached cables are isolated from this metal sheet by 0.5-millimeter thick insulating material. A Vertical Coupling Plane (VCP) grounded on the ground plane through the same configuration as in the HCP is used.

Test Standard

EN 55024:2010 (IEC 61000-4-2:2008)

Test level 3 for Air Discharge at ± 8 kV

Test level 2 for Contact Discharge at ± 4 kV

Test Level

Level	Test Voltage Contact Discharge ($\pm$ kV)	Test Voltage Air Discharge ($\pm$ kV)
1.	2	2
2.	4	4
3.	6	8
4.	8	15
X.	Special	Special

Performance criterion: B

Test Procedure

Air Discharge:

This test is done on a non-conductive surface. The round discharge tip of the discharge electrode shall be approached as fast as possible to touch the EUT. After each discharge, the discharge electrode shall be removed from the EUT. The generator is then re-triggered for a new single discharge and repeated 10 times for each pre-selected test point. This procedure shall be repeated until all the air discharge completed.

Contact Discharge:

All the procedure shall be same as Section 8.3.1 of IEC 61000-4-2, except that the tip of the discharge electrode shall touch the EUT before the discharge switch is operated.

Indirect discharge for horizontal coupling plane

At least 20 single discharges shall be applied to the horizontal coupling plane, at points on each side of the EUT. The discharge electrode positions vertically at a distance of 0.1 m from the EUT and with the discharge electrode touching the coupling plane.

Indirect discharge for vertical coupling plane

At least 20 single discharges shall be applied to the center of one vertical edge of the coupling plane. The coupling plane, of dimensions 0.5m × 0.5m, is placed parallel to, and positioned at a distance of 0.1m from the EUT. Discharges shall be applied to the coupling plane, with this plane in sufficient different positions that the four faces of the EUT are completely illuminated.

Test Data and Setup Photo

Environmental Conditions

Temperature:	25°C
Relative Humidity:	52 %
ATM Pressure:	100.0 kPa

The testing was performed by Andrew Shu on 2013-03-12.

Test Mode: Running

Table 1: Electrostatic Discharge Immunity (Air Discharge)

EN 61000-4-2 Test Points	Test Levels							
	-2 kV	+2 kV	-4 kV	+4 kV	-8 kV	+8 kV	-15 kV	+15 kV
Front (39 points)	A	A	A	A	A	A	/	/
Back (4 points)	A	A	A	A	A	A	/	/

Table 2: Electrostatic Discharge Immunity (Direct Contact)

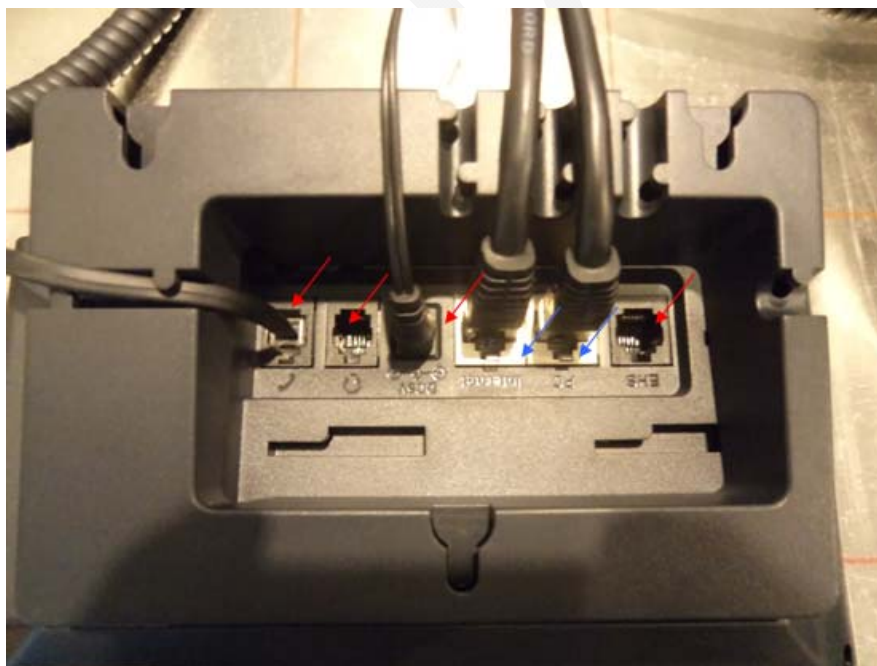
EN 61000-4-2 Test Points	Test Levels							
	-2 kV	+2 kV	-4 kV	+4 kV	-6 kV	+6 kV	-8 kV	+8 kV
Back (2 points)	A	A	A	A	/	/	/	/

Table 3: Electrostatic Discharge Immunity (Indirect Contact HCP)

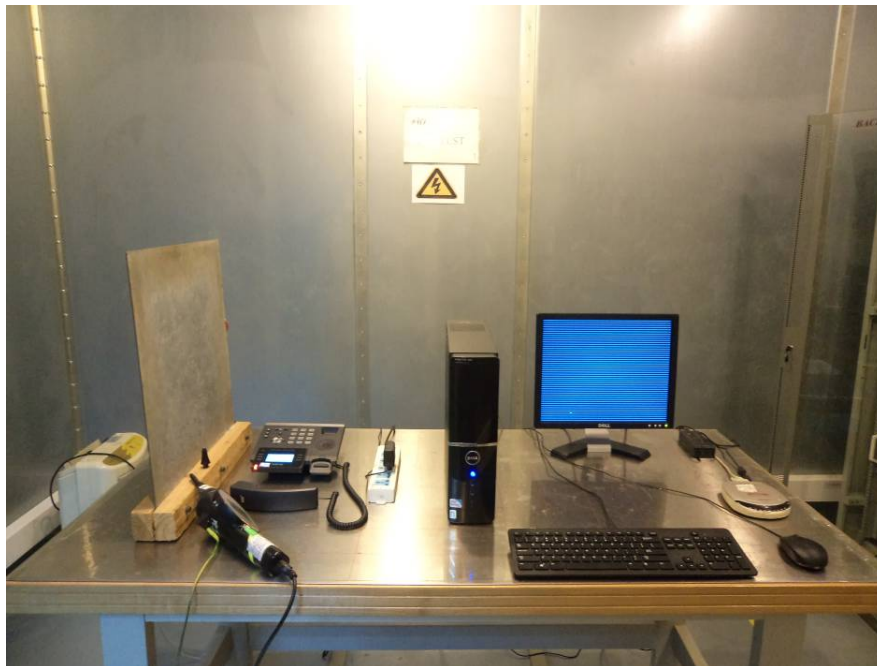
EN 61000-4-2 Test Points	Test Levels							
	-2 kV	+2 kV	-4 kV	+4 kV	-6 kV	+6 kV	-8 kV	+8 kV
Front Side	A	A	A	A	/	/	/	/
Back Side	A	A	A	A	/	/	/	/
Left Side	A	A	A	A	/	/	/	/
Right Side	A	A	A	A	/	/	/	/

Table 4: Electrostatic Discharge Immunity (Indirect Contact VCP)

EN 61000-4-2 Test Points	Test Levels							
	-2 kV	+2 kV	-4 kV	+4 kV	-6 kV	+6 kV	-8 kV	+8 kV
Front Side	A	A	A	A	/	/	/	/
Back Side	A	A	A	A	/	/	/	/
Left Side	A	A	A	A	/	/	/	/
Right Side	A	A	A	A	/	/	/	/



Note: —→ represents air discharge, —→ represents direct contact

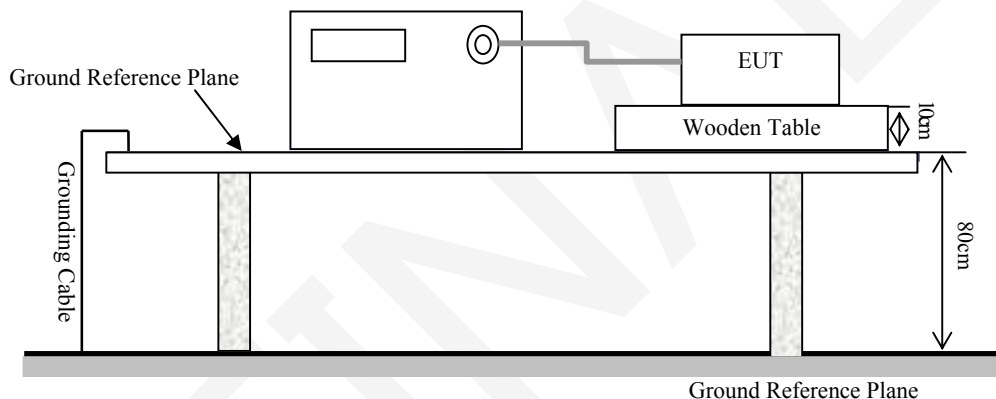


Test Setup Photos

EN 55024 §4.2.2-ELECTRICAL FAST TRANSIENTS (IEC 61000-4-4)**Test Equipment**

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	Ultra Compact Generator	UCS 500 N5	V0939105172	2012-11-24	2013-11-23
EM Test	Auto-transformer	MV2616	V0939105173	2012-11-24	2013-11-23
EM Test	EFT Clamp	HFK	0809/59	2012-11-24	2013-11-23

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements, traceable to National Primary Standards and International System of Units (SI).

Test System Setup**Test Standard**

EN 55024:2010 (IEC 61000-4-4:2004)
Test level 2 at 1 kV

Test Level

Open Circuit Output Test Voltage $\pm 10\%$		
Level	On Power Supply Lines	On I/O (Input/Output) Signal data and control lines
1	0.5 kV	0.25 kV
2	1 kV	0.5 kV
3	2 kV	1 kV
4	4 kV	2 kV
X	Special	Special

Performance Criterion: B

Test Procedure

The EUT was arranged for Power Line Coupling and for I/O Line Coupling through a capacitive clamp, where applicable. (Note: The I/O coupling test using a capacitive clamp is performed on the I/O interface cables that are longer in length than 3 meters.) A metal ground plane 2.4 meter by 2.0 meter was placed between the floor and the table and is connected to the earth by a 2.0 meter ground rod. The ground rod is connected to the test facility's electrical earth.

Test Data and Setup Photo

Environmental Conditions

Temperature:	25°C
Relative Humidity:	52 %
ATM Pressure:	100.0 kPa

The testing was performed by Andrew Shu on 2013-03-12

Test Mode: Running

IEC 61000-4-4 Test Points		Test Levels (kV)							
		+0.5	-0.5	+1.0	-1.0	+2.0	-2.0	+4.0	-4.0
AC mains power input ports	L1	/	/	/	/	/	/	/	/
	L2	/	/	/	/	/	/	/	/
	Earth	/	/	/	/	/	/	/	/
	L1+L2	A	A	A	A	/	/	/	/
	L1 + Earth	/	/	/	/	/	/	/	/
	L2 + Earth	/	/	/	/	/	/	/	/
	L1+L2+Earth	/	/	/	/	/	/	/	/
Signal ports	RJ45 Port	A	A	/	/	/	/	/	/

AC Mains Port



RJ45 Port

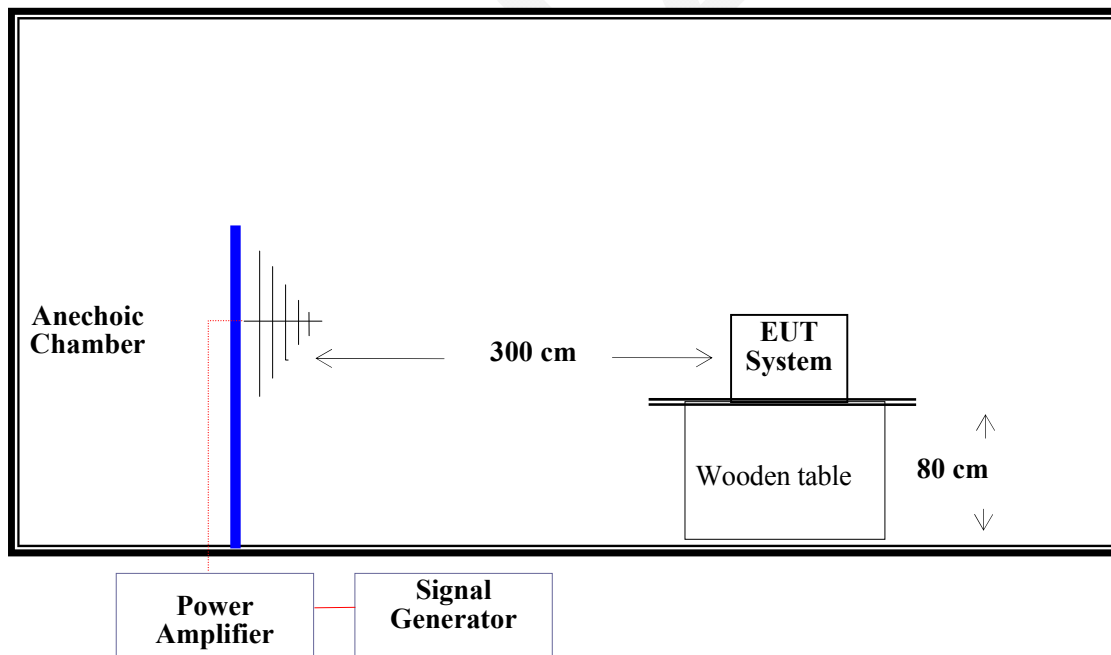


Test Setup Photos

EN 55024 §4.2.3.1-CONTINUOUS RADIATED DISTURBANCES (IEC 61000-4-3)**Test Equipment**

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
Amplifier Research	Amplifier	200W1000/M2	15893	2013-01-14	2014-01-13
Amplifier Research	Field Meter	FM5004	302149	2012-03-31	2013-03-30
ETS-LINDGREN	Sensor	HI-6005	N/A	2012-03-31	2013-03-30
HP	Signal Generator	8648C	3426A01345	2012-05-17	2013-05-16
Sunol Sciences	Bilog Antenna	JB1	A040904-2	2011-11-28	2014-11-27

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements, traceable to National Primary Standards and International System of Units (SI).

Test System Setup

Test Standard

EN 55024:2010 (IEC 61000-4-3: 2006 + A1:2007 + A2:2010)
Test level 2 at 3V / m

Test Level

Level	Field Strength V/m
1.	1
2.	3
3.	10
X.	Special

Performance Criterion: A**Test Procedure**

The EUT and its simulators are placed on a turn table which is 0.8 meter above the ground. The EUT is set 3 meters away from the transmitting antenna which is mounted on an antenna tower. Both horizontal and vertical polarizations of the antenna are set on test. Each of the four sides of EUT must be faced this transmitting antenna and measured individually. All the scanning conditions are as follows:

Condition of Test	Remarks
1. Field Strength	3 V/m (Test level 2)
2. Radiated Signal	AM 80%, 1 kHz Modulation
3. Scanning Frequency	80 – 1000 MHz
4. Sweeping time of radiated	0.0015decade/s
5. Dwell Time	1 sec.

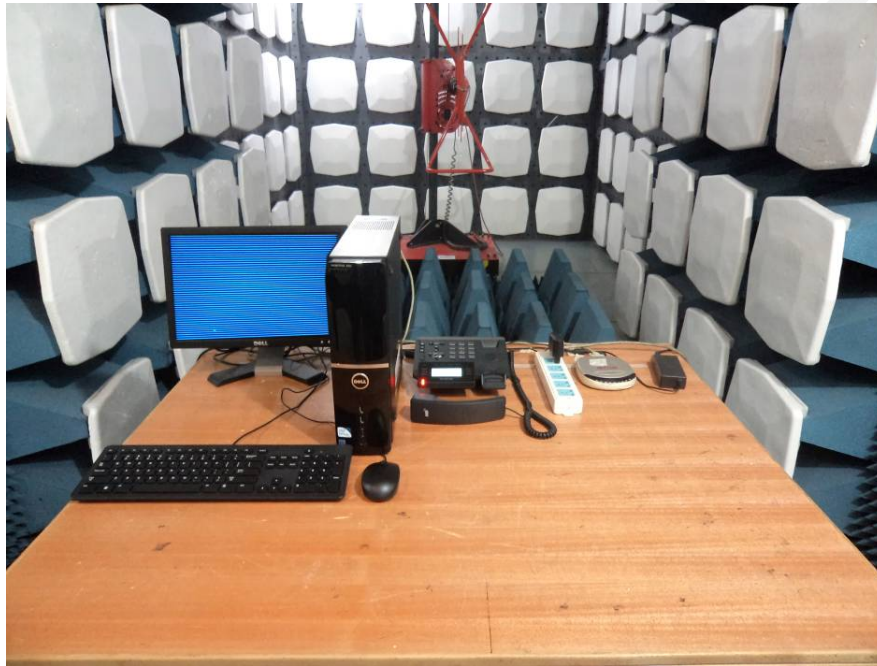
Test Data and Setup Photo**Environmental Conditions**

Temperature:	25 °C
Relative Humidity:	52 %
ATM Pressure:	100.0 kPa

The testing was performed by Andrew Shu on 2013-03-12.

Test Mode: Running

Frequency Range (MHz)	Front Side (3 V/m)		Rear Side (3 V/m)		Left Side (3 V/m)		Right Side (3 V/m)	
	VERT	HORI	VERT	HORI	VERT	HORI	VERT	HORI
80-1000	A	A	A	A	A	A	A	A

**Test Setup Photos**

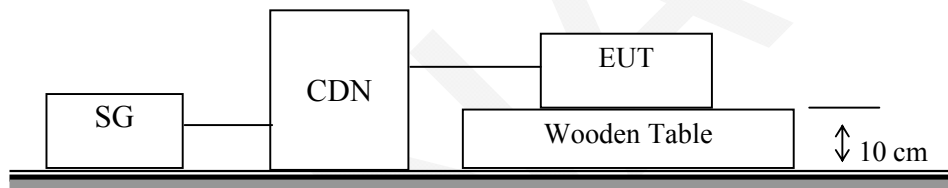
EN 55024 §4.2.3.2-CONTINUOUS CONDUCTED DISTURBANCES (IEC 61000-4-6)

Test Equipment

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	C/S Tester	CWS500	303277	2012-11-17	2013-11-16
EM Test	Attenuator	6dB	303282	2012-11-15	2013-11-14
EM Test	CDN	M3	1201-05	2012-11-24	2013-11-23
EM Test	CDN	T8RJ45	1101-04	2012-11-17	2013-11-16

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements, traceable to National Primary Standards and International System of Units (SI).

Test Setup



Test Standard

EN 55024:2010 (IEC 61000-4-6:2008)

Test Level 2 at 3 V r.m.s. (unmodulated), 0.15 MHz ~ 80 MHz

Test Level

Level	Voltage Level (r.m.s.) (V)
1	1
2	3
3	10
X	Special

Performance Criterion: A

Test Procedure

- 1) Let the EUT work in test mode and test it.
- 2) The EUT are placed on an insulating support 0.1 m high above a ground reference plane. CDN (coupling and decoupling device) is placed on the ground plane about 0.3 m from EUT. Cables between CDN and EUT are as short as possible, and their height above the ground reference plane shall be between 30 and 50 mm (where possible).
- 3) The disturbance signal described below is injected to EUT through CDN.
- 4) The EUT operates within its operational mode(s) under intended climatic conditions after power on.
- 5) The frequency range is swept from 150 kHz to 80 MHz using 3V signal level, and with the disturbance signal 80% amplitude modulated with a 1 kHz sine wave.
- 6) The rate of sweep shall not exceed 1.5×10^{-3} decades/s. Where the frequency is swept incrementally, the step size shall not exceed 1% of the start and thereafter 1% of the preceding frequency value.
- 7) Recording the EUT operating situation during compliance testing and decide the EUT immunity criterion.

Test Data and Setup Photo

Environmental Conditions

Temperature:	25°C
Relative Humidity:	52 %
ATM Pressure:	100.0 kPa

The testing was performed by Andrew Shu on 2013-03-12.

Test Mode: Running

Table 1: AC mains power input port

Modulation: Amplitude 80%, 1 kHz sine wave

Test level: 3V r.m.s.

Level	Voltage Level (r.m.s.) U_0	Pass	Fail
1	1	/	/
2	3	A	/
3	10	/	/
X	Special	/	/

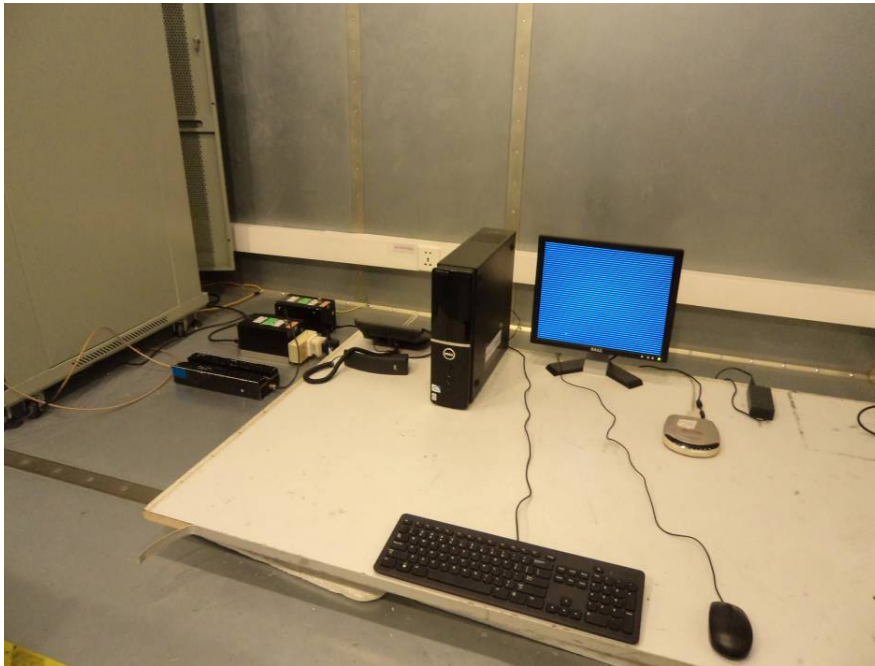
Table 2: RJ45 port

Modulation: Amplitude 80%, 1 kHz sine wave

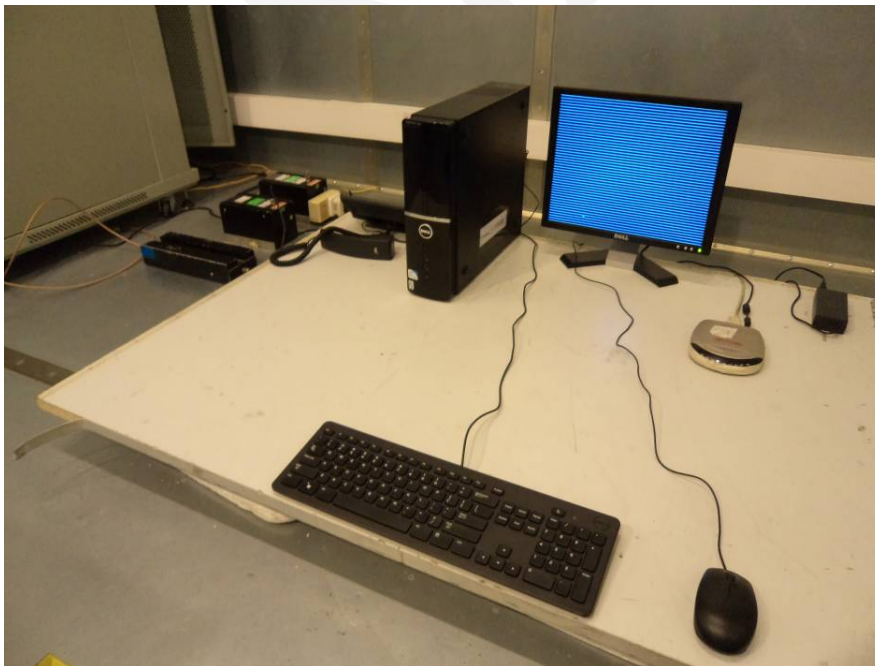
Test level: 3V r.m.s.

Level	Voltage Level (r.m.s.) U_0	Pass	Fail
1	1	/	/
2	3	A	/
3	10	/	/
X	Special	/	/

AC Mains Port



RJ45 Port

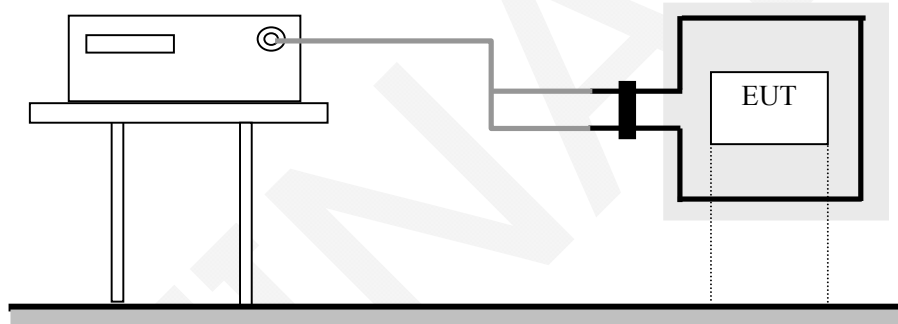


Test Setup Photos

EN 55024 §4.2.4-POWER FREQUENCY MAGNETIC FIELDS (IEC 61000-4-8)**Test Equipment**

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	Ultra Compact Generator	UCS500N5	V0939105172	2012-11-24	2013-11-23
EM Test	Auto-transformer	MV2616	V0939105173	2012-11-24	2013-11-23
Amplifier Research	Current Transformer	MC2630	301873	2013-03-09	2014-03-08
EM Test	Loop Antenna	MS100	0809-05	2012-11-17	2013-11-16

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements, traceable to National Primary Standards and International System of Units (SI).

Test Setup**Test Standard**

EN 55024:2010 (IEC 61000-4-8:2009)
Test level 1 at 1A/m

Test Level

Level	Magnetic Field Strength A/m
1	1
2	3
3	10
4	30
5	100
X.	Special

Performance criterion: A

Test Procedure

The EUT shall be subjected to the test magnetic field by using the induction coil of standard dimensions (1 m*1 m). The induction coil shall then be rotated by 90° in order to expose the EUT to the test field with different orientations.

Test Data and Setup Photo

Environmental Conditions

Temperature:	25 °C
Relative Humidity:	52 %
ATM Pressure:	100.0 kPa

The testing was performed by Andrew Shu on 2013-03-12.

Test Mode: Running

Level	Magnetic Field Strength A/m	X (Horizontal)	Y (Vertical)	Z (Special)
1	1	A	A	A
2	3	/	/	/
3	10	/	/	/
4	30	/	/	/
5	100	/	/	/
X	Special	/	/	/

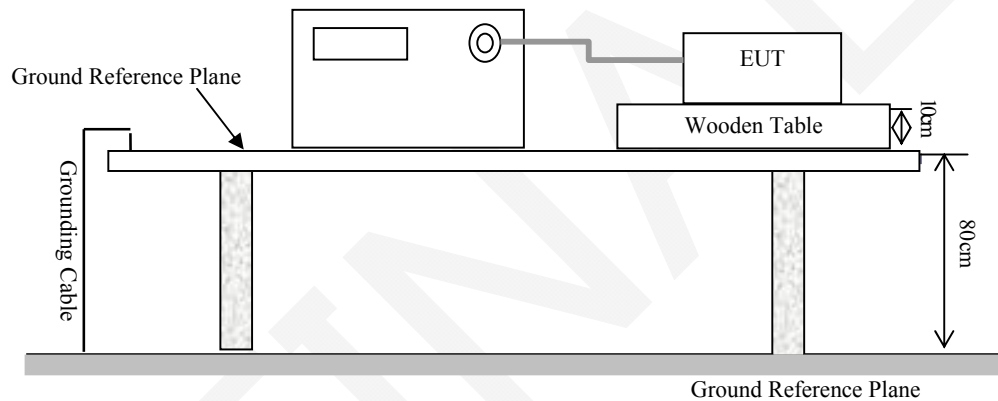


Test Setup Photos

EN 55024 §4.2.5-SURGES (IEC 61000-4-5)**Test Equipment**

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	Ultra Compact Generator	UCS 500 N5	V0939105172	2012-11-24	2013-11-23
EM Test	Auto-transformer	MV2616	V0939105173	2012-11-24	2013-11-23
EM Test	Coupling Decoupling Network	CNV 504N	V0939105174	2012-11-17	2013-11-16

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements, traceable to National Primary Standards and International System of Units (SI).

Test System Setup**Test Standard**

EN 55024:2010 (IEC 61000-4-5:2005)

AC Mains: L-N: Test level 2 at 1 kV

Signal port: Line-Ground: Test level 2 at 1 kV

Test Level

Level	Open Circuit Output Test Voltage $\pm 10\%$	Performance Criterion	
		AC Mains	Signal Port
1	0.5 kV	B	C
2	1 kV	B	C
3	2 kV	B	C
4	4 kV	B	C
X	Special	/	/

Test Procedure

- 1) For line to line coupling mode, provide a 1 kV 1.2/50 μ s voltage surge (at open-circuit condition) and a 8/20 μ s current surge into a short circuit. For line to ground coupling mode, provide a 1 kV 10/700 μ s voltage surge (at open-circuit condition).
- 2) At least 5 positive and 5 negative (polarity) tests with a maximum 1/min repetition rate are conducted during test.
- 3) Different phase angles are done individually.
- 4) Record the EUT operating situation during compliance test and decide the EUT immunity criterion for above each test.

Test Data and Setup Photo

Environmental Conditions

Temperature:	25°C
Relative Humidity:	52 %
ATM Pressure:	100.0 kPa

The testing was performed by Andrew Shu on 2013-03-12.

Test Mode: Running

Table 1: AC mains power input port

Level	Voltage	Poll	Path	Pass	Fail
1	0.5kV	$\pm$	L-N,	A	/
2	1kV	$\pm$	L-N	A	/
3	2kV	$\pm$	L-PE, N-PE,L-N-PE	/	/
4	4kV	$\pm$	L-N, L-PE, N-PE	/	/

Table 2: RJ45 port

Level	Voltage	Poll	Path	Pass	Fail
1	0.5kV	$\pm$	Line-Ground	A	/
2	1kV	$\pm$	Line-Ground	A	/
3	2kV	$\pm$	Line-Line, Line-Ground	/	/
4	4kV	$\pm$	Line-Line, Line-Ground	/	/

AC mains Port



RJ45 Port

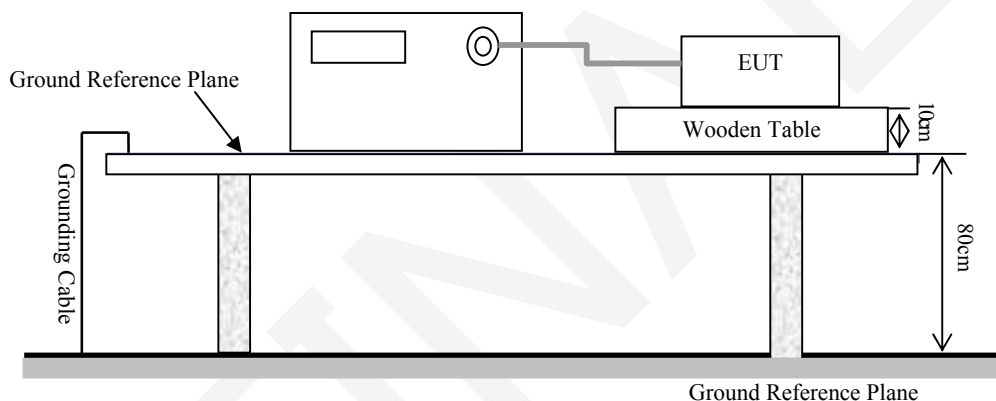


Test Setup Photos

EN 55024 §4.2.6-VOLTAGE DIPS AND INTERRUPTIONS (IEC 61000-4-11)**Test Equipment**

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	Ultra Compact Generator	UCS 500 N5	V0939105172	2012-11-24	2013-11-23
EM Test	Auto-transformer	MV2616	V0939105173	2012-11-24	2013-11-23

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements, traceable to National Primary Standards and International System of Units (SI).

Test Setup**Test Standard**

EN 55024:2010 (IEC 61000-4-11:2004)
Test levels and Performance Criterion

Test Level

Test Level	Voltage dip and short interruptions %UT	Duration (Periods)	Performance Criterion
1	>95	0.5	B
2	30	25	C
3	>95	250	C

Test Procedure

- 1) The interruption is introduced at selected phase angles with specified duration.
- 2) Record any degradation of performance.

Test Data and Setup Photo**Environmental Conditions**

Temperature:	25°C
Relative Humidity:	52 %
ATM Pressure:	100.0 kPa

The testing was performed by Andrew Shu on 2013-03-12.

Test Mode: Running

Level	U2 (% Reduction)	Td(Periods)	Phase Angle	N	Pass	Fail
1	0	0.5	0/180	3	A	/
2	70	25	0/180	3	A	/
3	0	250	0/180	3	C	/



Test Setup Photo

EN 61000-3-2 – HARMONIC CURRENT EMISSIONS

According to EN 61000-3-2-2006 + A1:2009 + A2:2009 section 7: Equipment with a rated power of 75 W or less, other than lighting equipment, are not included in this standard.

FINAL

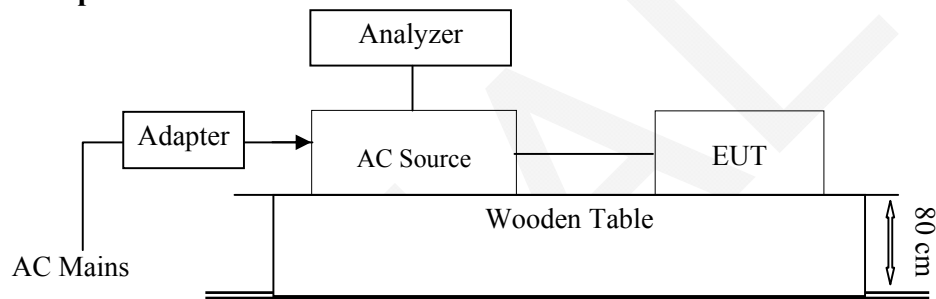
EN 61000-3-3 – VOLTAGE FLUCTUATION AND FLICKER

Test Equipment

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	Harmonic/Flicker Analyzer	DPA 500N	V0939105176	2012-11-24	2013-11-23
EM Test	AC Source	ACS500	303276	2011-04-11	2013-04-10

*** Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements, traceable to National Primary Standards and International System of Units (SI).

Test System Setup



Test Standard

EN 61000-3-3:2008

Flicker Test Limits:

The limits shall be applicable to voltage fluctuations and flicker at the supply terminals of the equipment under test, measured or calculated according to clause 4 under test conditions described in clause 6 and annex A. Tests made to prove compliance with the limits are considered to be type tests.

The following limits apply:

- the value of Pst shall not be greater than 1,0;
- the value of Plt shall not be greater than 0,65;
- the value of d(t) during a voltage change shall not exceed 3,3 % for more than 500 ms;
- the relative steady-state voltage change, dc, shall not exceed 3,3 %;
- the maximum relative voltage change dmax, shall not exceed
 - a) 4 % without additional conditions;
 - b) 6 % for equipment which is:
 - switched manually, or
 - switched automatically more frequently than twice per day, and also has either a delayed restart (the delay being not less than a few tens of seconds), or manual restart, after a power supply interruption.

NOTE: The cycling frequency will be further limited by the Pst and Plt limit. For example: a dmax of 6 % producing a rectangular voltage change characteristic twice per hour will give a Plt of about 0.65.

c) 7 % for equipment which is

- attended whilst in use (for example: hair dryers, vacuum cleaners, kitchen equipment such as mixers, garden equipment such as lawn mowers, portable tools such as electric drills), or
- switched on automatically, or is intended to be switched on manually, no more than twice per day, and also has either a delayed restart (the delay being not less than a few tens of seconds) or manual restart, after a power supply interruption.

In the case of equipment having several separately controlled circuits in accordance with 6.6, limits b) and c) shall apply only if there is delayed or manual restart after a power supply interruption; for all equipment with automatic switching which is energized immediately on restoration of supply after a power supply interruption, limits a) shall apply; for all equipment with manual switching, limits b) or c) shall apply depending on the rate of switching. Pst and Plt requirements shall not be applied to voltage changes caused by manual switching. The limits shall not be applied to voltage changes associated with emergency switching or emergency interruptions.

Test Data and Setup Photo

Environmental Conditions

Temperature:	24°C
Relative Humidity:	56 %
ATM Pressure:	100.1 kPa

Date of test:	17:39 28 Feb. 2013
Tester:	Andrew Shu
Standard used:	EN 61000-3-3 Flicker
Long time (Pst):	10 min
Observation time:	10 min (1 Flicker measurement)
Flicker meter:	230V / 50Hz
Customer:	Yealink (Xiamen) Network Technology Co., Ltd.
E. U. T.:	IP Phone
Model:	T42G
EUT Operation Mode:	Running

Maximum Flicker results

	EUT values	Limit	Result
Pst	0.028	0.65	Pass
Plt	0.028	1.00	Pass
dc [%]	0.012	3.30	Pass
dmax [%]	0.093	4.00	Pass
dt [s]	0.000	0.50	Pass

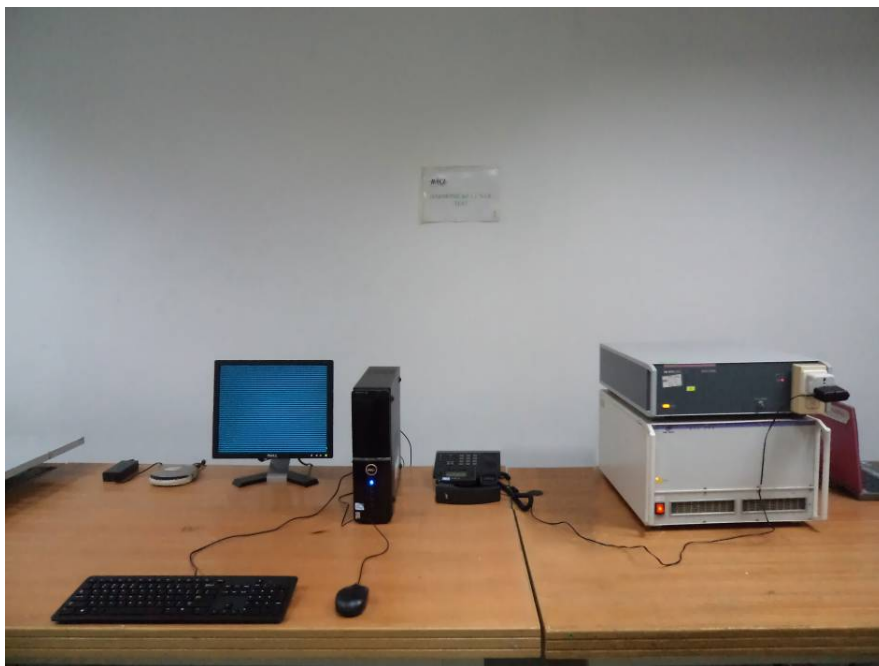
**Test Setup photo**

EXHIBIT A - PRODUCT LABELING

Proposed CE Label Format



Specification: Text is Black or white in color and is left justified. Labels are printed in indelible ink on permanent adhesive backing and shall be affixed at a conspicuous location on the EUT or silk-screened onto the EUT.

Proposed Label Location on EUT



EXHIBIT B - EUT PHOTOGRAPHS

EUT – All View



EUT (Base) – Front View



EUT (Base) – Rear View



EUT (Base) – Top View



EUT (Base) – Bottom View



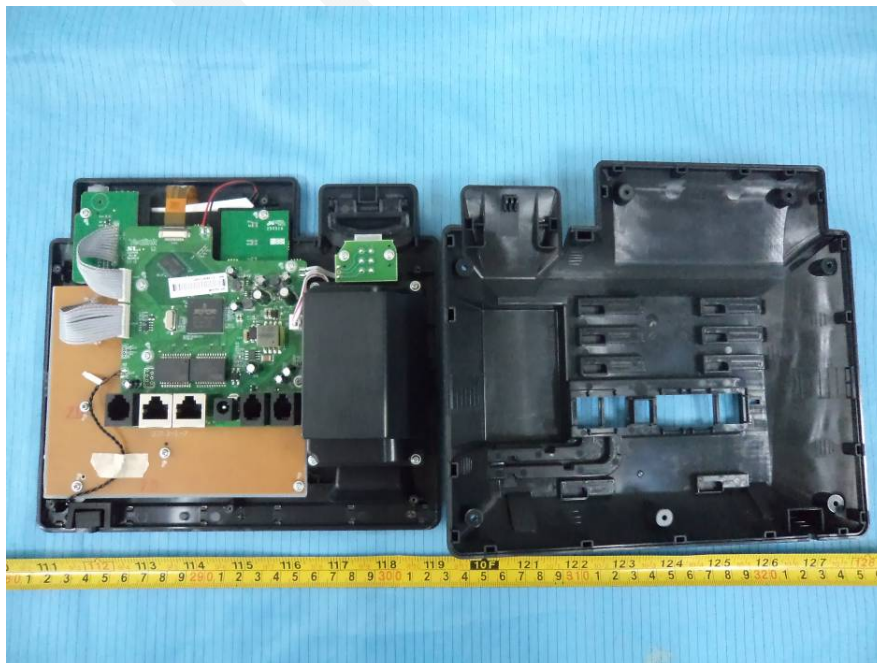
EUT (Base) – Left View



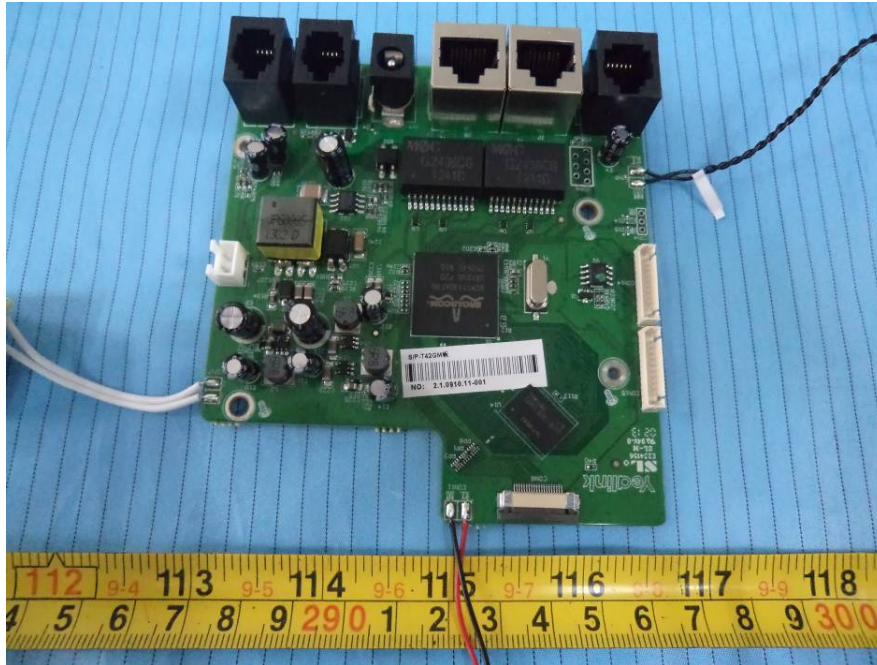
EUT (Base) – Right View



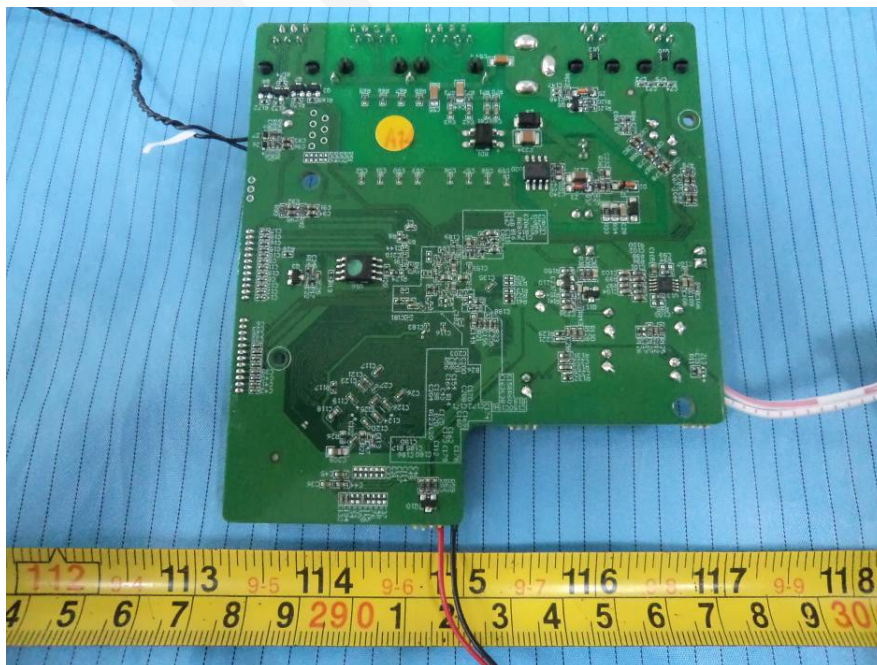
EUT (Base) – Cover off View



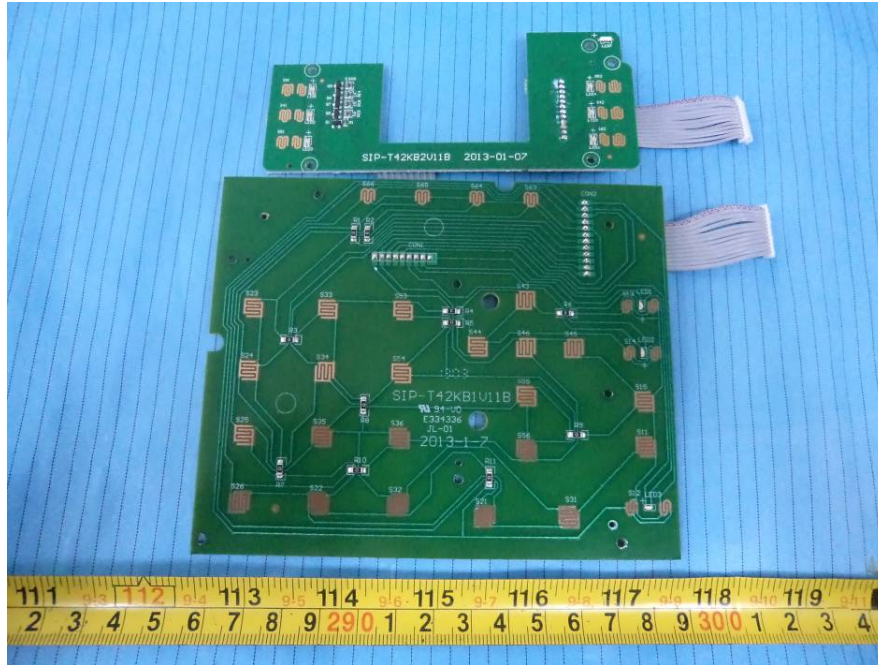
EUT (Base) – Main Board Top View



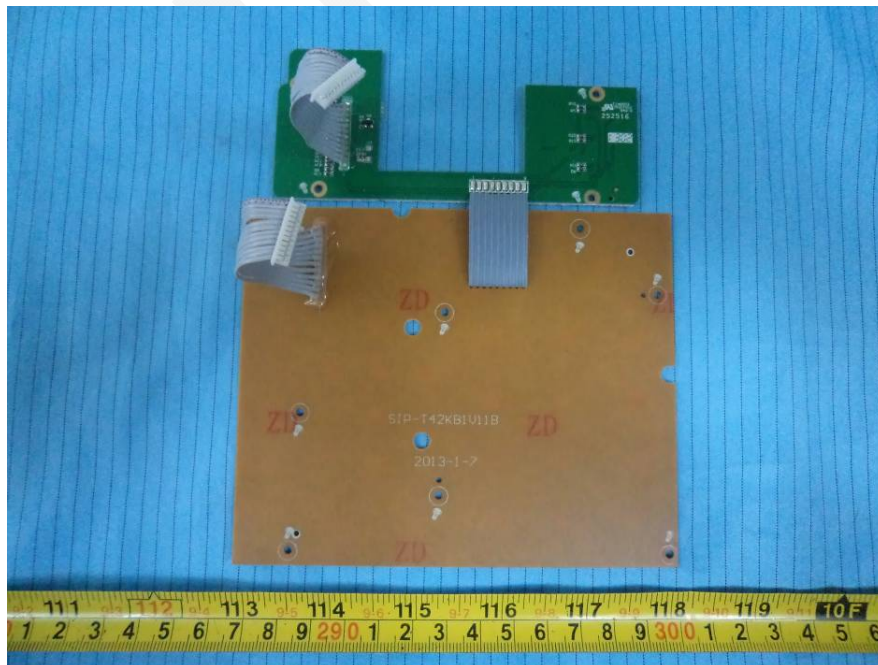
EUT (Base) – Main Board Bottom View



EUT (Base) – Key Board Top View



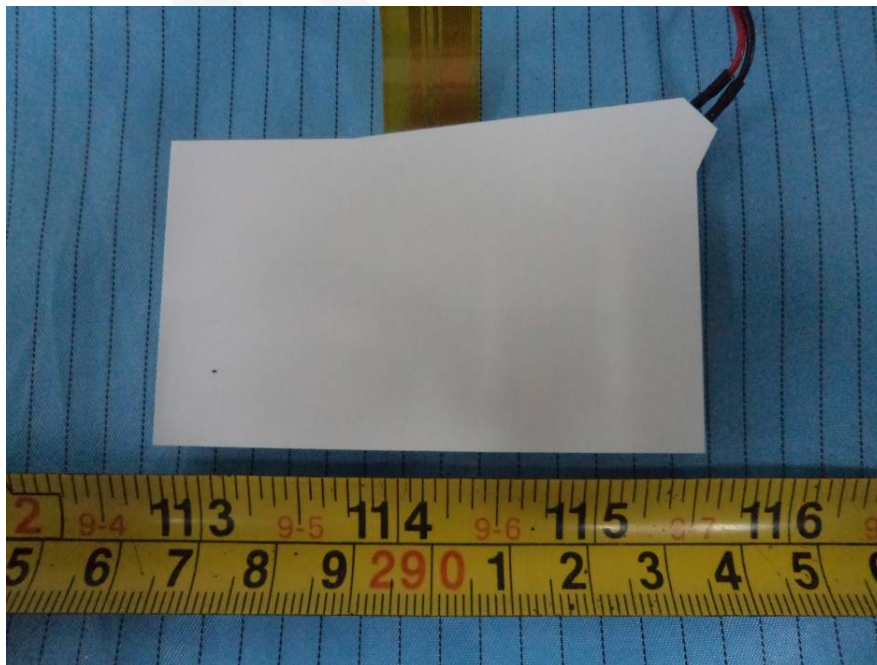
EUT (Base) – Key Board Bottom View



EUT (Base) – LCD Top View



EUT (Base) – LCD Bottom View



EUT (Handset) – Front View



EUT (Handset) – Rear View



EUT (Handset) – Cover off View



EUT – Adapter View



EUT – Adapter Label View



EXHIBIT C - TEST SETUP PHOTOGRAPHS

Conducted Disturbance at Mains Terminals - Front View (Powered by Adapter)



Conducted Disturbance at Mains Terminals - Side View (Powered by Adapter)



Conducted Disturbance at Telecommunication Port - Front View (Powered by Adapter)



Conducted Disturbance at Telecommunication Port - Side View (Powered by Adapter)



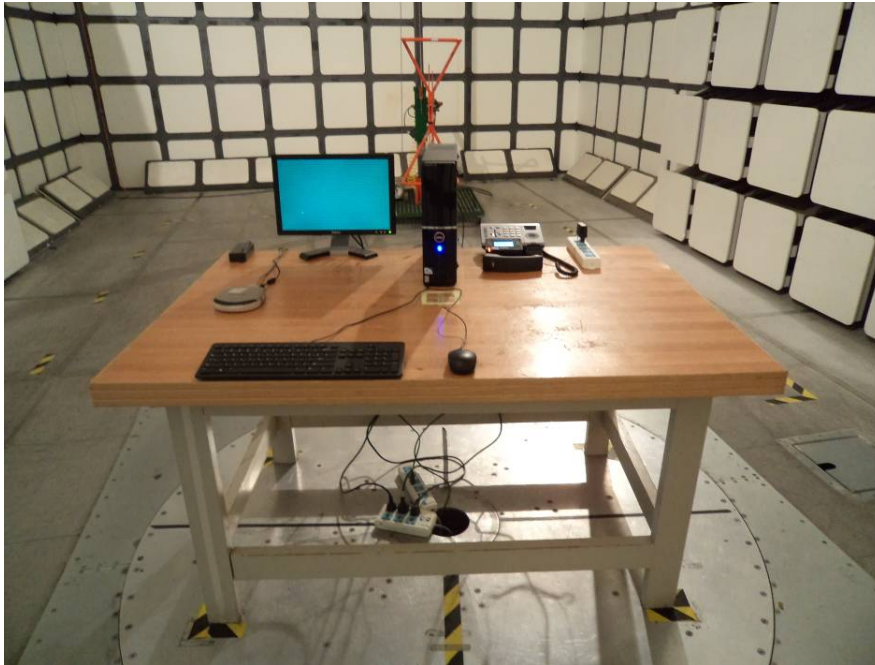
Conducted Disturbance at Mains Terminals - Front View (Powered by PoE)



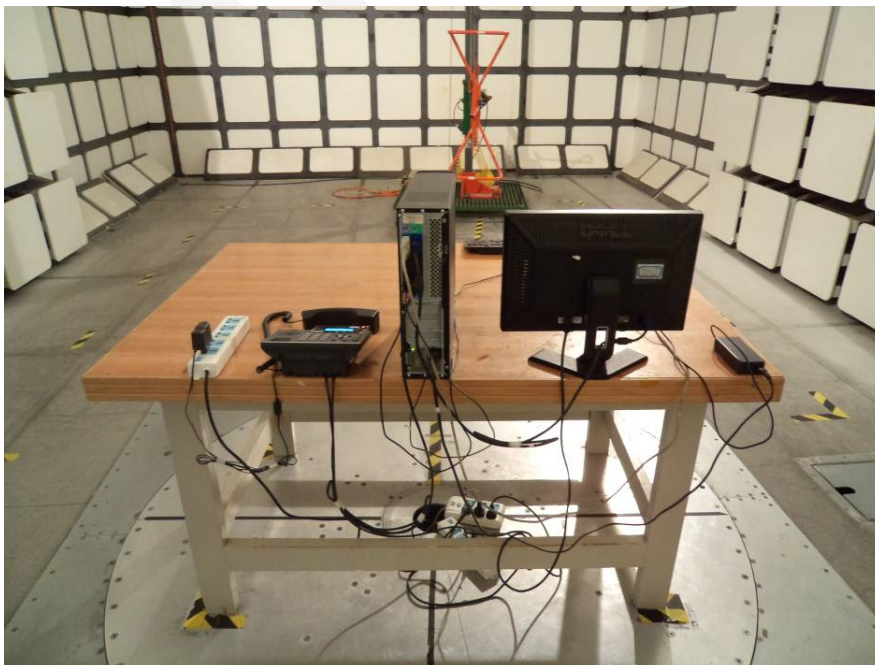
Conducted Disturbance at Mains Terminals - Side View (Powered by PoE)



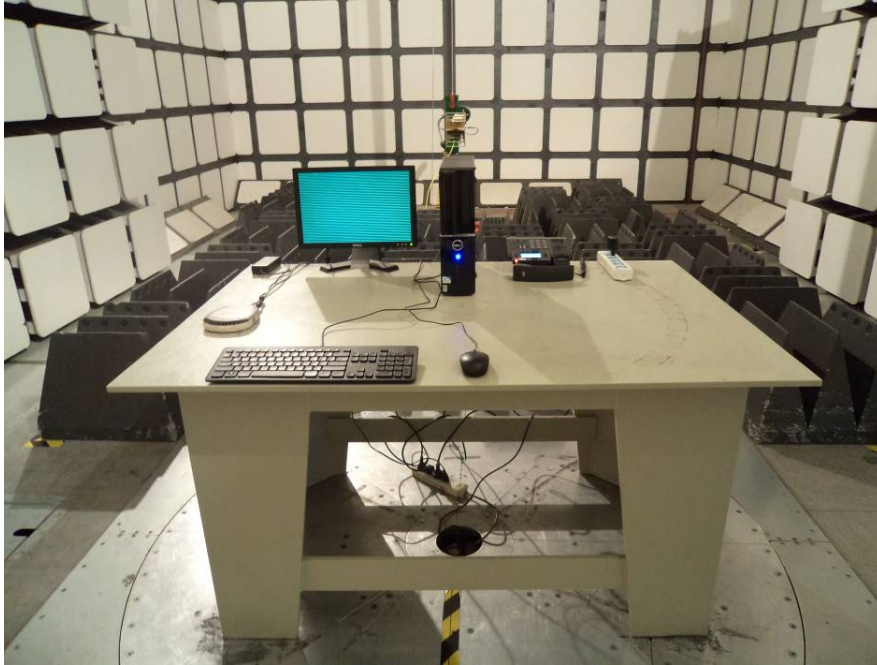
Radiated Disturbance - Front View (Below 1 GHz, Powered by Adapter)



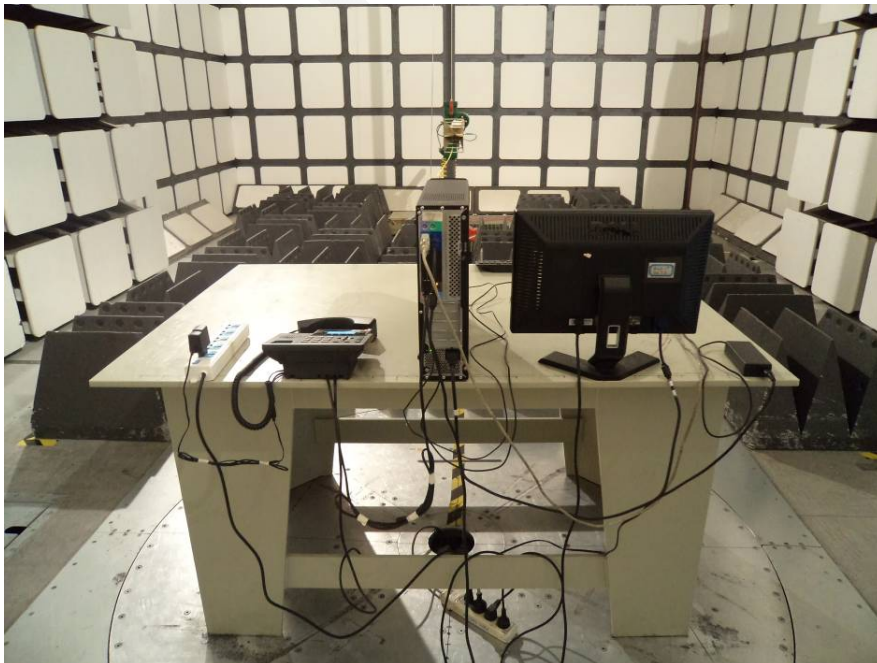
Radiated Disturbance - Rear View (Below 1 GHz, Powered by Adapter)



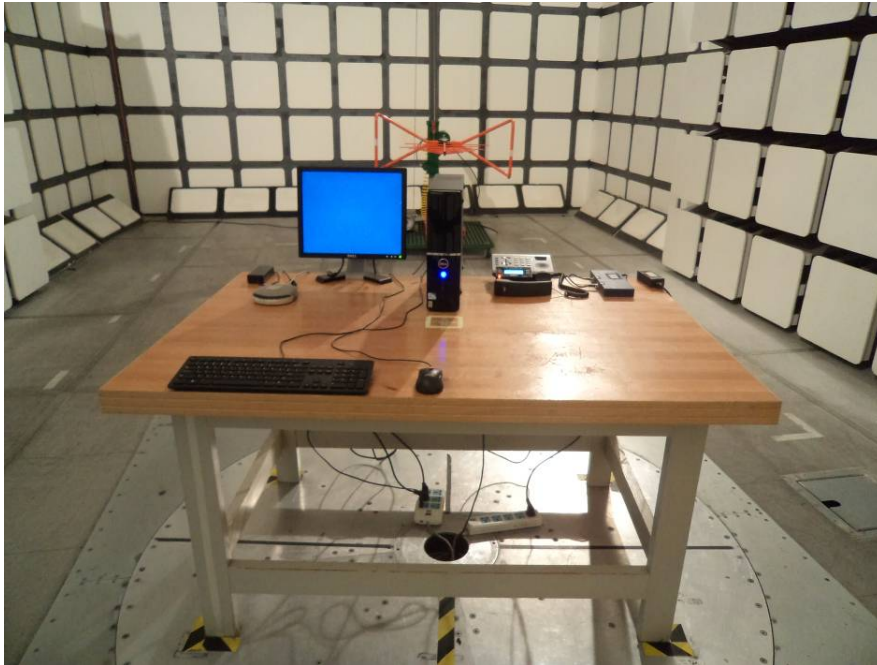
Radiated Disturbance – Front View (Above 1 GHz, Powered by Adapter)



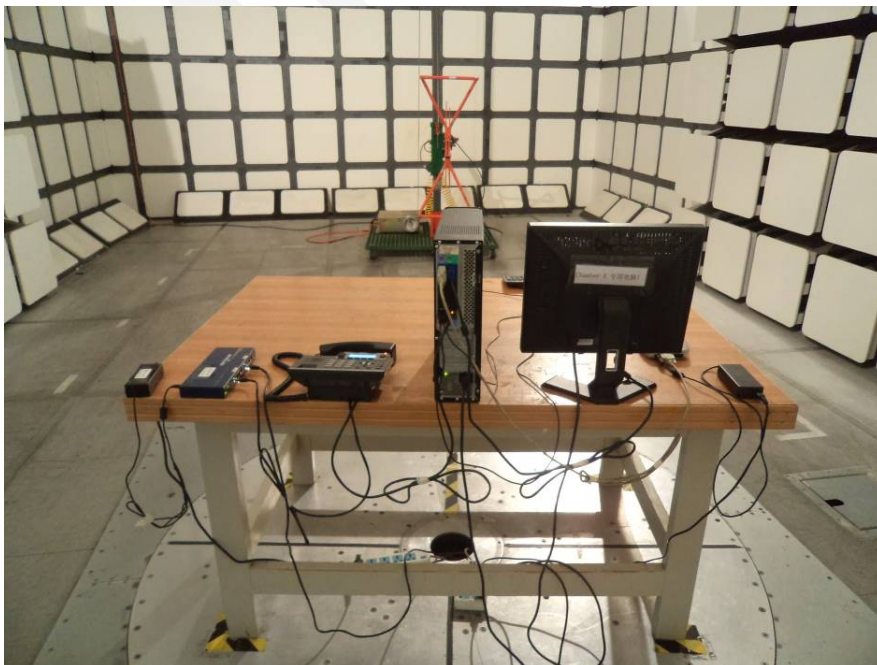
Radiated Disturbance – Rear View (Above 1 GHz, Powered by Adapter)



Radiated Disturbance - Front View (Below 1 GHz, Powered by PoE)



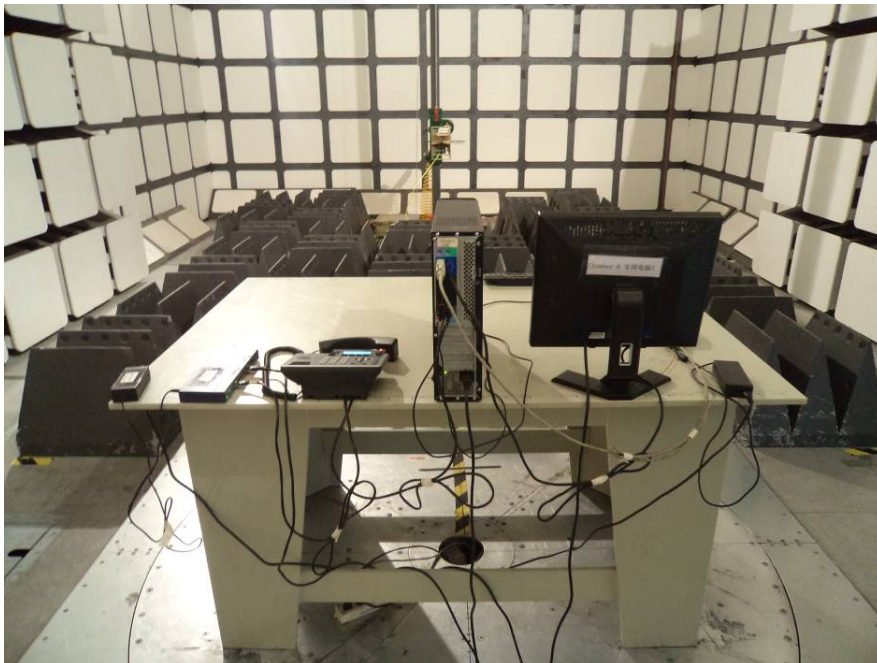
Radiated Disturbance - Rear View (Below 1 GHz, Powered by PoE)



Radiated Disturbance – Front View (Above 1 GHz, Powered by PoE)



Radiated Disturbance – Rear View (Above 1 GHz, Powered by PoE)



******* END OF REPORT *******